

LabMaster 10 Zi-A-R* High Bandwidth Modular Oscilloscopes 20 GHz - 100 GHz



Key Features

- Up to 100 GHz Industry leading analog bandwidth
 - 4 channels at 36 GHz
 - 2 channels at 65 GHz
 - 1 channels at 100 GHz
- Up to 240 GS/s sample rate
- Long Memory Up to 1.5Gpt/ch
- Modular Design build system with up to 80 36 GHz channels
- ChannelSync™ Architecture for 130 fs matching between channels
- Multi-Lane eye, Jitter and Noise Analysis with SDAIII-CompleteLinQ
- Optical Modulation Analysis with Optical-LinQ
- PAM4 Eye, Jitter and Noise Measurements with PAM4 Signal Analysis
- Industries only true hardware
 14.1 GB/s serial trigger

The LabMaster 10 Zi-A series of real-time oscilloscopes boasts the world's highest bandwidh and fastest sampling rate at 100 GHz and 240 GS/s. This world-leading performance is key to acquiring, analyzing and understanding the fastest phenomena found in R&D labs, where engineers are working on next-generation communication systems, high bandwidth electrical components and fundamental scientific research.

The Fastest Oscilloscope for the Most Demanding Signals

Whether working on communications technology capable of terabit/s symbol rates, analyzing the quickest and most energetic laser pulses, or building links using very high speed NRZ or PAM4 signals, the LabMaster 10 Zi-A Series oscilloscopes can acquire and analyze the waveforms.

For those who need more than two channels at the industries highest bandwidths, multiple LabMaster aquisition modules can be combined with one Master Control Module to build a system of up to 80 channels @ 36 GHz, 40 channels @ 65 GHz, or even 20 channels at 100 GHz.

Sophisticated Software for Sophisticated Analysis

The LabMaster 10 Zi-A Series offers an extensive set of standard math tools and add-on software packages that integrate seamlessly into the oscilloscope "MAUI" interface. LabMaster 10 Zi-A oscilloscopes excel at performing in-depth analysis of complicated signals. For NRZ signals, the SDAIII-CompleteLinQ package compares eye, jitter and noise on up to four lanes, simultaneously. With the Optical-LinQ package, analyze coherent optical signals such as DP-QPSK, DP-16QAM. Additionally, the PAM4 Signal Analysis package performs eye, jitter and noise measurements on PAM4 signals. Since the fastest signals often require custom analysis. LabMaster 10 Zi-A also comes standard with the ability to run MATLAB scripts in-stream.

World's Highest Bandwidth Real-Time Oscilloscope

LabMaster 10 Zi-A modular oscilloscopes break bandwidth, sample rate, and channel count barriers providing more "bandwidth density" than any other oscilloscope. Its modular design provides the simplest upgrade path in bandwidth and number of channels. In one acquisition module, it provides four channels at 36 GHz with the ability to use 20 modules, for 80 channels simultaneously.

Performance across multiple modules is guaranteed with ChannelSync, which ensures precise synchronization of all channels in all acquisition modules using a single distributed 10 GHz clock and a single trigger circuit. Synchronization is identical to that provided with a single oscilloscope, <130fsrms jitter between all channels.

The modular design means the LabMaster 10 Zi-A is future proof and upgrading is easy. Start with one acquisition module and add more channels or higher bandwidth modules later as needed.

No bitrate or symbol rate is too high for the LabMaster 10 Zi-A with industry leading bandwidth and sample rate. LabMaster 10 Zi-A is perfect for 10-16 Gb/s technologies such as 40/100 GBASE-R Ethernet, SAS12, and PCI Express Gen4 that benefit from 80 GS/s on four or more channels at up to 36 GHz. Ultra-high speed technologies, such as CEI-25/28, CEI-56, and coherent optical formats including DP-QPSK, 16-QAM, MIMO benefit from 65 or 100 GHz bandwidths and four or more channels.



A LabMaster 10 Zi-A oscilloscope that provides one channel at 100 GHz, two channels at 65 GHz and four channels at 36 GHz



Add up to twenty acquisition modules for 20 channels at 100 GHz, 40 channels at 65 GHz or 80 channels at 36 GHz.

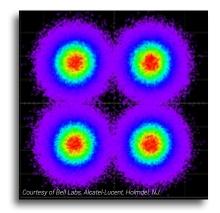
- World's Highest Performing Real-Time Oscilloscope 100 GHz bandwidth, (3.5 ps risetime_{20 – 80%}), 240 GS/s sample rate, up to 1.5 Gpts of analysis memory
- 2. Modular start with four channels and grow the system over time.
- 3. Wide bandwidth upgrade range from 20 to 100 GHz provides long-term investment protection
- **4.** ChannelSync architecture utilizes a 10 GHz distributed clock for precise alignment of all acquisition systems
- 5. Single trigger circuit for all modules eliminates additive trigger jitter that occurs with 10 MHz clocking and trigger synchronization of multiple conventional oscilloscopes
- **6.** Simple modular setup, just connect and acquire signals.
- 325 MB/s data transfer rate from the LabMaster to a separate PC with Teledyne LeCroy Serial Interface Bus (LSIB) option
- 8. Server-class multi-core processor combines with X-Stream II streaming architecture for fast acquisition and analysis — 20 cores of processing power and 32 GB of RAM standard, expandable to 192 GB
- 9. Utilize the built-in 15.3" widescreen (16 x 9) high resolution WXGA color touch screen display or connect a monitor with up to WQXGA 2560 x 1600 pixel resolution
- **10.** Highly stable timebase (50fs_{rms}) over long acquisitions, low Jitter Measurement and Rj noise floor.
- **11.** Deepest standard toolbox with more measurements, more math, more power
- 12. Eye Doctor™ II and Virtual Probe Signal Integrity Toolsets provide real-time de-embedding, emulation, and equalization on serial data channels
- **13.** Up to 14.1 Gb/s Serial Trigger available 80-bit NRZ, 8b/10b and 64b/66b symbol triggering

FASTEST DIGITIZER FOR THE FASTEST SIGNALS

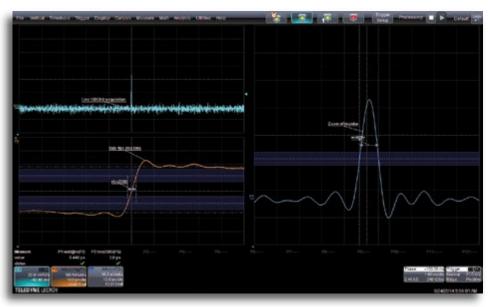
For over 30 years, Teledyne LeCroy has consistently shown industry leadership by pushing forward the limits of oscilloscope performance and waveshape analysis. The LabMaster 10 Zi-A continues this tradition of engineering excellence, incorporating custom chip design and patented innovations to reach unprecedented digitization performance: 100 GHz bandwidth and 240 GS/s sample rate.

Capturing and Characterizing the Fastest Phenomena

Scientific research of phenomena that occur at the shortest timescales require the fastest digitization speeds. At 240 GS/s, samples are acquired at time intervals of 4.17 ps, 50% faster than the next-fastest digitizer, yielding excellent signal reconstruction. For applications and experiments requiring multi-channel, the patented ChannelSync architecture provides



I & Q components from 160 GBaud QPSK signals are captured by a two-channel LabMaster 10-100Zi-A oscilloscope.

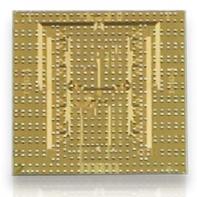


Acquisition and analysis of femtosecond laser pulse by LabMaster 10-100Zi-A.

matching between channels that is unrivaled: <130 fs channel-to-channel jitter. Such precision is not possible with conventional methods of synchronizing two independent oscilloscopes. This synchronization is key for applications requiring closely matched channels, such as optical modulation analysis.

Custom Chip Design

The LabMaster 10 Zi-A acquisition system utilizes multiple custom monolithic ICs, including designs for the track & hold, analog-to-digital converters and fast acquisition memory. These designs are at the heart of our industry-leading 4 channel 36 GHz, 80 GS/s design. No other 4-channel oscilloscope on the market achieves 36 GHz bandwidth.



Digital Bandwidth Interleaving

Digital Bandwidth Interleaving uses high-precision diplexers and mixers to split the input signal into separate 36 GHz bands for digitization, and recombines them to achieve record breaking bandwidths. DBI technology, first used in 2005, is now in its 8th generation in the LabMaster 10-100Zi-A, where it is almost triples the 36 GHz ADC bandwidth to 100 GHz. In the LabMaster 10-65Zi-A, DBI is used in a doubler configuration to achieve 65 GHz bandwidth.

ENABLING HIGH-SPEED SERDES DEVELOPMENTS

LabMaster 10 Zi-A is uniquely suited to the demands of the high-speed SerDes market. For differential signalling requirements, the LabMaster 10-65Zi-A provides two channels at 65 GHz. and accurately characterizes 28 - 32 Gb/s signals. Oscilloscope risetime_{20 - 80}% is an impressive 4.9 ps, a necessary speed when the unit interval (UI) is a mere 36 ps wide (or less). The 1024 Mpts/Ch acquisition memory provides the ability to capture very long waveforms, permitting deterministic jitter (Dj) decomposition on long patterns - something not possible in a sampling oscilloscope. Two input channels provides the ability to input a differential signal pair into the oscilloscope, eliminating the bandwidth, noise, and accuracy constraints inherent in a separate, external differential amplifier.

Multiple Configurations Provide Flexibility

In addition to 2 channels at 65 GHz. a LabMaster 10 Zi-A system will also provide 4 channels at 36 GHz for testing and debugging of multiple lanes at lower bandwidth. This can be especially useful for crosstalk analysis or lane skew testing when multiple lanes are deployed. Thus, a 65 GHz LabMaster can deployed in a variety of ways and serve many important application needs in the same lab. For the fastest digitization possible, use the 100 GHz LabMaster 10-100Zi-A acquisition module. Multiple MCM-Zi-A Master Control Modules and Acquisition Modules can even be mixed and matched as needs change.

Superior Serial Data/Crosstalk Analysis and Debug Tools

Teledyne LeCroy's SDAIII-CompleteLinQ Serial Data and Crosstalk Analysis products provide unique capability to simultaneously calculate, display and compare eye diagrams, jitter and noise measurements from four separate lanes or one lane probed or modeled in four different locations. EyeDoctorII and VirtualProbe tools use S-parameters to de-embed/emulate fixtures and interconnects and show you the signal where you can't put a probe. Use the optional 14.1 Gb/s true-hardware serial trigger for capturing rare events. A variety of serial decode annotations are available for common encoding schemes, as well as serial protocols. Teledyne LeCroy's combination of serial decoders and ProtoSync™ protocol analysis views permits link layer debugging on initial SerDes transmissions before protocol analyzer hardware is typically available.



WORLD'S LEADING OPTICAL MODULATION ANALYZER

LabMaster 10 Zi-A combines
the world's fastest real-time
bandwidth and four input
channels with pristine signal
fidelity to meet the advanced
research and development
requirements for optical coherent
modulation analysis on long-haul
telecommunication systems.

The World's Leading Optical Modulation Analyzer (OMA)

Teledyne LeCroy and Coherent
Solutions Ltd have teamed up to bring
you the world's highest performing
OMA. The analyzer is comprised of a
LabMaster 10 Zi-A oscilloscope and
a Coherent Solutions IQScope-RT
Series Coherent Optical Receiver,
that is seamlessly integrated and
controlled by the oscilloscope
software. The integrated Optical-LinQ
analysis software was co-developed
by Teledyne LeCroy and Coherent
Solutions.

Premiere Performance

No other OMA on the market delivers the performance of the Teledyne LeCroy / Coherent Solutions OMA. DP-QPSK signals with baud rates up to 130 GBaud are detectable by integrating an industry leading coherent receiver (with 70 GHz electrical bandwidth) with a 4-channel LabMaster 10-65Zi-A oscilloscope. The analyzer runs the Optical-LinQ software package, which includes all of the software tools and DSP algorithms to completely characterize the optical signal under test.



OMA with LabMaster 10-65Zi-A and IQScope-RT (Option HBW)

OMA system bandwidth: 65 GHz Max detectable baud rate: 130 GBaud



OMA with LabMaster 10-36Zi-A and IQScope-RT (Option SBW)

OMA system bandwidth: 36 GHz Max detectable baud rate: 72 Gbaud

IQScope-RT Series Coherent Optical Receiver

- Up to 70 GHz electrical outputs for X & Y polarization of I & Q signals.
- Built in LO, C and/or L band
- Laser wavelength/frequency and power adjustable via Optical-LinQ or front panel



COMPLETE ANALYSIS WITH OPTICAL-LINQ

The Optical-LinQ software package performs optical modulation analysis when using either the integrated Coherent Solutions IQScope-RT or other coherent receiver.

Extensive set of analysis tools

The Optical-LinQ software from Coherent Solutions includes an extensive selection of visualizations that let users gain a complete understanding of the quality and impairments in the transmitted optical signal. Visualizations include constellations, trajectories, eye diagrams and tracks, of I, Q, phase EVM, and much more. Parametric measurements include EVM%, I & Q Bias Error, Quad Error, IQ Skew and offset. See the OMA brochure for complete information.

True BER analysis

Optical-LINQ offers both quick and convenient BER Estimates along with true and accurate BER counting capabilities. The BER set up panel allows the configuration of the coding scheme from one of the common preset options, or any custom-defined bit sequence and multiplex options.



Analysis of a DP-QPSK optical signal.

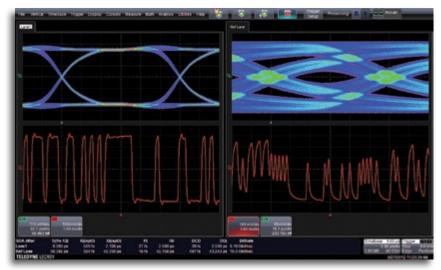
Use Built-in or Custom DSP Algorithms

Test and validation of digital signal processing (DSP) algorithms is a vital part of the transceiver development. Optical-LINQ is equipped with built-in DSP algorithms for polarization demultiplexing, dispersion compensation and carrier recovery such as CMA, MMA, and Viterbi & Viterbi to use as tested reference algorithms. The custom code integration feature permits validation of custom algorithms in MATLAB format.

Complete Modulation Format Support

Optical-LINQ comes with pre-set support for many of the common optical modulation formats, including QPSK, 16QAM and 64QAM. If you are developing or working with non-conventional modulation formats, you can define your own format using Optical-LINQ's powerful custom modulation format definition capability

SDAIII-CompleteLinQ SERIAL DATA ANALYSIS PRODUCTS



The Teledyne LeCroy SDAIII-CompleteLinQ Serial Data Analysis products contain multilane eye and jitter analysis, LaneScape™ comparison modes, vertical noise measurements, and crosstalk analysis tools. These capabilities provide the deepest insight into the behavior of multi- or single-lane serial data systems.

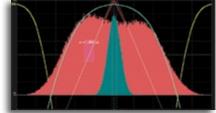
SDAIII Core Toolset

Teledyne LeCroy provides the most complete toolset in the industry for jitter measurements and eye diagram/ jitter analysis. Rj and Dj are separated and Dj is decomposed using one of three dual-Dirac algorithms. Eye diagrams containing all acquired unit intervals are rendered 10-100x faster than competitive systems. Eye diagram analysis tools, such as the extrapolated

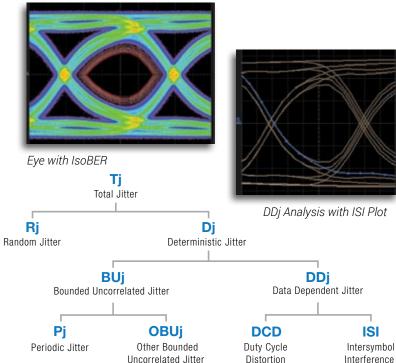
IsoBER plot, aid insight. Multiple additional tools. such as Tracks. Histograms, and Spectrum waveforms. enhance the understanding of jitter causes.

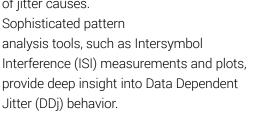
Sophisticated pattern

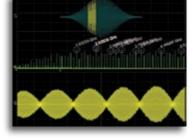
Jitter (DDj) behavior.



Rj+BUj Analysis







Pj Analysis



Three Jitter Methodologies

Choose from three dual-Dirac models to separate jitter into total, random and deterministic components (Ti, Ri, Di). The Spectral Ri Direct method determines Ri directly from the jitter spectrum, and is the most used algorithm. Spectral Rj+Dj CDF Fit follows the FibreChannel MJSQ model. In situations where large amounts of crosstalk/BUj raise the spectral noise floor, the NQ-Scale method will provide more accurate separation of Ri and Di, and therefore more accurate Ti results.

OPTIONAL SDAIII UPGRADES

Measure up to 4 Lanes Simultaneously

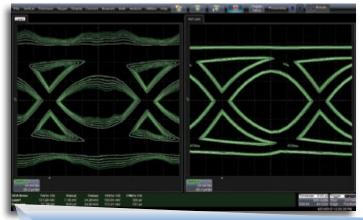
"LinQ" products provide extensive multi-lane analysis capabilities. Quickly understand lane-to-lane differences in jitter measurements, eye diagrams, and jitter analysis. Perform aggressor on/off analysis, and see the results from both scenarios simultaneously. Save the analysis of a particular scenario to the Reference Lane, and configure a LaneScape™ Comparison mode to compare the Reference to either one, two or all lanes. Each "lane" can be a different serial data lane, or a different analysis of data from a single serial data lane - ideal for comparing different equalization schemes (using Eye Doctor II option) or

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examining system behaviors at different locations in the lane (using probes or the VirtualProbe option).

Vertical Noise and Crosstalk

The Crosstalk and CrossLinQ packages provide vertical noise measurements and crosstalk analysis tools for



SDA Noise EH(1e-12) Tn(1e-12) Rn(sp) Dn(sp) EW(1e-12) Lane1 131.28 mV 7.18 mV 34.39 mV 105.04 mV 125 ps 33.38 mV 646 µV Ref Lane 24.93 mV 172.41 mV 131 ps

complete aggressor/victim analysis. Use one of three dual-Dirac models to measure and separate noise into total (Tn), random (Rn) and deterministic (Dn) components, and further decompose Dn into Intersymbol Interference Noise (ISIn) and Periodic Noise (Pn). Only Teledyne LeCroy performs this analysis on real-time oscilloscopes. Similar to jitter analysis, noise can be viewed as a noise track, histogram and spectrum, providing insight into the vertical noise resulting from coupling to other active serial data lanes or other interference sources. The Crosstalk Eye shows the probabilistic extent of noise both inside and outside the eye, quickly showing the impact of excessive noise that is not

possible to see in a traditional eye diagram.

CompleteLinQ Does it All

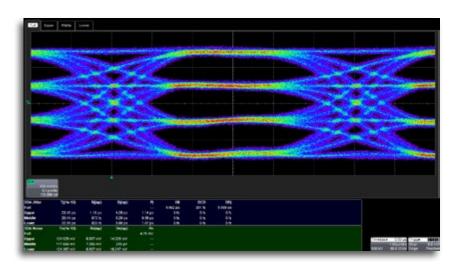
The CompleteLinQ user interface framework provides easy access to all features described above, and also integrates EyeDoctorII and VirtualProbe capabilities for Tx/Rx equalization and fixture/channel de-embedding/emulation. Order SDAIII-CompleteLinQ to equip your oscilloscope with all of Teledyne LeCroy's Serial Data Analysis and Signal Integrity tools.





EYE, JITTER AND NOISE ANALYSIS OF PAM4 SIGNALS

PAM4 signaling is seen as the next step in the evolution of serial data signal formats, allowing two bits of information to be transmitted per UI rather than one. Next generation standards from OIF and IEEE including CEI-56G-VSR and 100GBASE-KP4 utilize PAM4 signaling. Teledyne LeCroy's PAM4 analysis package extends our industry-leading eye, jitter and noise analysis capabilities to perform a complete analysis of all three eye openings in a PAM4 signal.



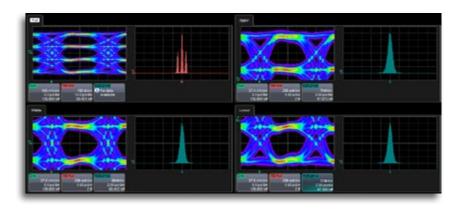
Measure Eye, Jitter and Noise

For each of the three eye openings, the PAM4 software package performs a complete analysis to determine the eye openings, jitter and noise as a function of BER. Measurements for each opening include: Eye Height, Width Tj, Rj, Dj, Tn, Rn and Dn. Mean and RMS vales for each level are also determined, as well as periodic noise and jitter results.

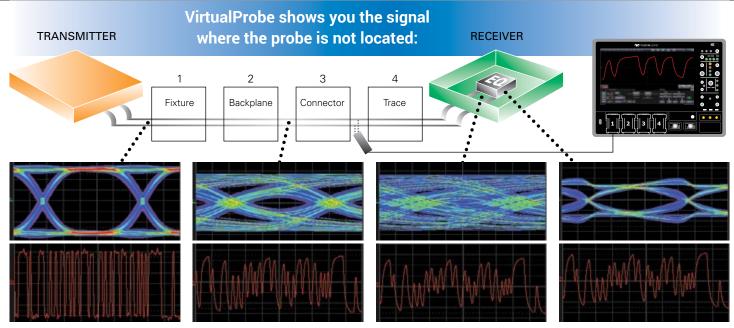


Deeper Understanding with Additional Views of Jitter and Noise

The PAM4 package includes the views of noise and jitter utilized in the SDAIII-CompleteLinQ package. Enhance understanding of jitter and noise by displaying histograms, spectra, bathtub and IsoBER curves for each eye opening. PAM4 analysis is compatible with EyeDoctorII, allowing users to de-embed channel and fixture effects, emulate a channel, or apply equalization.



EYEDOCTOR™II AND VIRTUALPROBE SIGNAL INTEGRITY TOOLS



Virtually probe the signal at the transmitter with the fixture present, and then de-embed its effects form the measurement.

View the signal between structures to understand losses, ISI and crosstalk caused by backplanes, interconnects and connectors.

See what the eye looks like at the receiver - even if it is not in reach of a differential probe.

Use EyeDoctor to open the eye by modeling CTLE, FFE and DFE equalizers used by your receiver.

As signal speeds and data rates continue to rise, signal integrity effects such intersymbol interference (ISI) and crosstalk become more prevalent and challenging. Use Teledyne LeCroy's Advanced Signal Integrity tools to transform your measured signal to include the effects of de-embedding, emulation and equalization algorithms.

De-embed, Equalize and Emulate with EyeDoctorII

Curious to know what your signal would look like without fixture effects? Do you need to understand how ISI and crosstalk of a modeled channel will affect your jitter margin? Or are you seeking to determine which equalization schemes will do the best job of opening a closed eye? The EyeDoctorII package includes easy configuration of basic de-embed/emulation scenarios, CTLE, DFE and FFE equalizers, and transmitter emphasis/de-emphasis.

Advanced De-embedding, Emulation and Virtual Probing

The VirtualProbe package expands the de-embedding and emulation capabilities of EveDoctorII. Configure a multi-block circuit using modeled S-parameters or measured with a Teledyne LeCroy SPARQ (or other VNA), and VirtualProbe will build the transfer function that returns the signal as it would appear before or after any block in the circuit. The electrical behavior of a block to reflect and transmit signals can be included, added or removed in order to de-embed or emulate fixtures or channels. Probe loading effects can also be removed. When used in conjunction with the Crosstalk, CrossLinQ or CompleteLinQ SDAIII options, crosstalk between lanes can be modeled using 8 and 12-port S-parameters. Use the Teledyne LeCroy SPARQ to measure these S-parameters at a fraction of the price of a VNA.

Use EyeDoctorII and VirtualProbe with SDAIII CompleteLinQ products

When using EyeDoctorII and VirtualProbe on oscilloscopes enabled within the SDAIII-CompleteLinQ products, configure de-embedding, emulation and equalization from the same simple flow-chart dialog as all other serial data analysis features. When enabled with the "LinQ" option to enable 4 lanes, users can configure EyeDoctorII and VirtualProbe configurations on each lane, facilitating rapid comparisons of different de-embedding and equalization setups.

Learn More

teledynelecroy.com/dl/1023 teledynelecroy.com/vid/M0T6WEC0JYQ teledynelecroy.com/dl/1216 teledynelecroy.com/dl/1136

MOST COMPLETE DEBUG SOLUTION

Connecting a problem with its root cause often requires viewing the signal in multiple domains. The LabMaster 10 Zi-A allows you to combine multiple analysis types into a single, correlated display:

- Analog signals
- Protocol decodes
- Eye diagrams
- Jitter and noise breakdown
- Measurement parameters
- Frequency-domain traces

Serial Decode—A Whole New Meaning to Insight

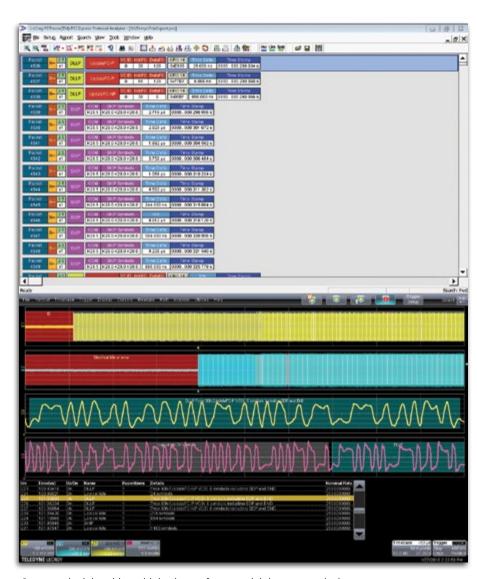
Over 19 different protocols are supported with serial decoders. Use ProtoSync with PCIe, USB, SATA, SAS, and Fibre Channel to get a dual-display view of both oscilloscope-generated decode annotations and protocol analyzer software views. Search on protocol data in a table and export table data to an Excel file.

Learn More

teledynelecroy.com/dl/3005

More Trigger Capability Isolates More Problems Quickly

12 GHz Edge trigger, 14.1 Gb/s truehardware serial trigger (optional, includes capability for 80-bit NRZ and 8b/10b symbol, ten different SMART triggers, four-stage Cascade™ triggering, Measurement trigger, and TriggerScan™ are all standard and allow you to isolate the problem quickly and begin to focus on the cause.



Get more insight with multiple views of your serial data transmissions.

Search and Scan to Understand

Search a captured waveform for hundreds of different measurement parameters or other conditions using WaveScan. Set complex conditions, view search results on the waveform and in a table, and quickly zoom and jump to an entry. "Scan" for events that can't be triggered in hardware.

DEEP INSIGHT CLARIFIES COMPLEX SIGNALS

All Oscilloscope Tools are Not Created Equal

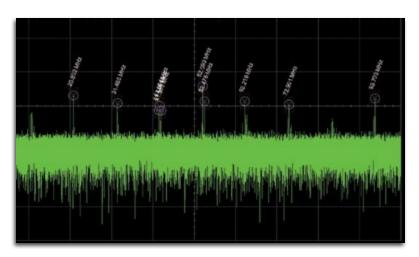
LabMaster 10 Zi has the deepest standard toolbox of any oscilloscope, providing more measure, math, graphing, statistical, and other tools, and more ways to leverage the tools to get the answer faster. While many other oscilloscopes provide similar looking tools, Teledyne LeCroy allows the most flexibility in applying the tools to any waveform.

Customized Tools

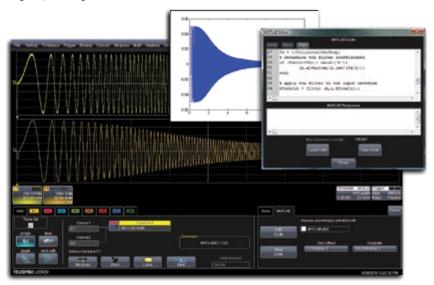
Only Teledyne LeCroy completely integrates third party programs into the oscilloscope's processing stream by allowing you to create and deploy a new measurement or math algorithm directly into the oscilloscope environment and display the result on the oscilloscope in real-time! There is no need to run a separate program, or ever leave the oscilloscope window. Use C/C++, MATLAB, Excel, JScript (JAVA), and Visual Basic to create your own customized math functions, measurement parameters, or other control algorithms.

Graphical Track, Trend, and Histogram Views

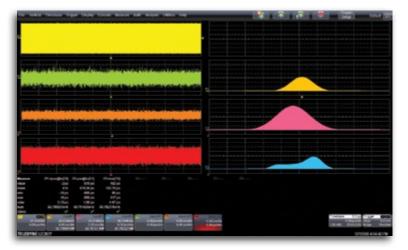
Track plots measurement values on the Y-axis and time on the X-axis to display a measurement change time-correlated to the original channel acquisition—perfect for intuitive understanding of behaviors in frequency modulated (FM) or pulse width modulated (PWM) circuits and jitter measurements, including modulation or spikes. Histograms provide a visual distribution representation of a large sample of measurements, allowing faster insight. Trends are ideal for plotting slow changes in measurement values.



X-Stream II fast throughput streaming architecture makes difficult analysis and deep insight possible. Above, an FFT is applied to a 50 Mpts waveform to determine root cause failure. The high frequency resolution this provides enables deep insight into signal pathologies.



XDEV Customization software package being used to implement a 1 MHz Butterworth filter using MATLAB®.



Capture a single clock channel (yellow) and display Track graphs and Histograms simultaneously of multiple jitter parameters.

MODULAR DESIGN FOR EXPANDABILITY

LabMaster 10 Zi-A leverages the unique LabMaster ChannelSync architecture with next-generation 8HP SiGe chipsets to produce the world's highest bandwidth, four channel oscilloscope – 36 GHz. When combined with patented DBI technology, bandwidth nearly doubles and triples, to 65 GHz and 100 GHz, with sample rates of 160 GS/s and 240 GS/s.

LabMaster 10 Zi-A oscilloscopes are fundamentally better – they are modular, inherently upgradeable, and infinitely flexible while retaining all the simplicity of operation expected from a conventional oscilloscope. LabMaster 10 Zi-A oscilloscopes can be configured for massive numbers of channels at up to 100 GHz – completely eliminating technology and test barriers.

ChannelSync technology ensures precise synchronization of all channels in all acquisition modules by using a single-distributed 10 GHz clock and a single trigger circuit. External clocking is not required, and trigger jitter from multiple trigger circuits is non-existent. Jitter between all channels is an ultra-low <130 fs_{rms}. Conventional 10 or 100MHz reference clocks simply cannot achieve this level of performance. Multi-module synchronization performance is identical to that provided with a single, standard oscilloscope package, and all captured waveforms and analysis appears on one oscilloscope display.

Typical LabMaster 10 Zi-A Systems

The Master Control Module (which includes the display) simply and quickly connects to one or more acquisition modules to create a functional, single oscilloscope package, but without the normal input channel or bandwidth limitations—operation is the same as a conventional oscilloscope. All waveforms are viewable on the built-in 15.3" display or on a variety of optional or user-supplied displays (up to 2560 x 1600 resolution). The entire system design speaks to a level of sophistication and integration not seen before in laboratory equipment.



4 Channels at 36 GHz

The base configuration is a LabMaster MCM-Zi-A Master Control Module and a single Acquisition Module. This provides four channels at up to 36 GHz and 80 GS/s. Acquisition modules are available at 20, 25, 30 and 36 GHz.



4 Channels at 65 GHz 8 Channels at 36 GHz

Buld a 4-channel 65 GHz oscilloscope by connecting two acquisition modules. This system can also be used as an 8-channel, 36 GHz oscilloscope. In addition to 65 GHz acquisition modules, 50 and 59 GHz units are available.



The OC910 oscilloscope cart is ideal for housing systems with up to 4 acquisition modules.

Maximum Flexibility

Start with one Master Control Module and one Acquisition Module. Upgrade Acquisition Modules to include more memory or more bandwidth. Add additional acquisition modules at any time without returning equipment to the factory for modification or re-calibration.

Master Control Module

The LabMaster MCM-Zi-A Master Control Module provides the display, control panel, CPU, and ChannelSync 10 GHz distributed clock to provides precise and unmatched synchronization between all oscilloscope channels. High-speed PCIe cables connect to the acquisition modules for control and data transfer. The MCM-Zi-A includes a server-class CPU with Xeon™ E5-2680 v2 processors and 32 GB of RAM standard (up to 192 GB optional). Coupled with Teledyne LeCroy's X-Stream II architecture, the CPU muscles its way through the immense amounts of acquisition data made possible by LabMaster 10 Zi-A.

Additional Acquisition Modules

LabMaster 10 Zi-A acquisition modules are available at a variety of bandwidths, from 20 GHz to 100 GHz. All modules include four channels at 36 GHz bandwidth. The 50, 59, and 65 GHz models also provide 2 channels at the rated bandwidth; the 100 GHz module includes 1 channel. Each acquisition module is tightly integrated to the Master Control Module (MCM-Zi-A) with a ChannelSync 10 GHz distributed clock and two PCIe cables. Up to 20 acquisition modules can be used in one system. All acquired data is sent to the server-class CPU for processing.

ChannelSync Mainframe Hub

Easily expand beyond 5 acquisition modules with the LabMaster CMH-20Zi ChannelSync Mainframe Hub. The CMH-20Zi synchronizes up to 80 channels at 36 GHz with the same <130 fs precise performance as 4-channel system. The hub redistributes the 10 GHz clock and PCle synchronization signals to up to 20 acquisition modules. One "card" is used for each connected acquisition module; cards can be purchased at any time to minimize the upfront cost.



OPTICAL-TO-ELECTRICAL CONVERTER (0E695G)



Teledyne LeCroy's OE695G wide-band optical-to-electrical converter is ideal for measuring optical datacom and telecom signals with data rates from 622 Mb/s to 12.5+ Gb/s. Connection to a real-time Teledyne LeCroy oscilloscope is through the 2.92 mm interface, with a provided adapter to connect to ProLink interfaces.

Built-in Reference Receiver

The OF695G contains built-in software reference receiver filters for common Fiber Channel, Ethernet, and ITU telecom standards. These reference receiver filters provide a 4-pole Bessel Thompson low pass filter response for the combined oscilloscope and optical-to-electrical (O-E) system with the -3dBe (electrical) at 0.75*bit rate. Combined passband response (compared to ideal) is ±1.6dBe (typical). If desired, a custom reference receiver for any bit rate up to 12.5Gb/s can also be applied. Additionally, the OE695G can be operated without any reference receiver applied, providing 9.5 GHz of bandwidth at -3 dB and Tr(10-90%) of approximately 45 ps when used with a Teledyne LeCroy oscilloscope of \geq 20 GHz of bandwidth.

Calibration Option for Maximum Accuracy

If guaranteed reference receiver response is required (±0.85 dB max through the passband, with a relaxed requirement through 1.5*bit rate, per the reference receiver requirement), the optional OE695G-REFCAL may be ordered with the OE695G. This will provide a documented calibration response for the various standard reference receivers and up to 12.5Gb/s "custom" reference receiver on all four oscilloscope channels at specific gain ranges (with typical response provided at other gain ranges).

Key Features

- Compatible with LabMaster 10 Zi oscilloscopes
- Frequency range DC to 9.5 GHz (electrical, -3 dB)
- Reference receiver support from 8GFC to 10GFC FEC, or Custom (<12.5Gb/s)
- Full bandwidth mode (no reference receiver applied)
- 62.5/125 μm multi-mode or single-mode fiber input
- Broad wavelength range (750 to 1650 nm)
- +7 dBm (5 mW) max peak optical power
- Low noise (as low as 25 pW/√Hz)
- Ideal for Eye Mask, Extinction Ratio, and Optical Modulation Amplitude (OMA) testing

HIGH BANDWIDTH PROBING SOLUTIONS

Ultra-wideband Architecture for Superior Signal Fidelity

Teledyne LeCroy's WaveLink® high bandwidth differential probes utilize advanced differential traveling wave (distributed) amplifier architecture to achieve superior high frequency analog broadband performance.

Highest Bandwidth (25 GHz) Solder-In Lead

Up to 25 GHz Solder-In performance with system (probe + oscilloscope) rise times equal to that of the oscilloscope alone.

Ultra-compact Positioner (Browser) Tip

The most compact positioner tip browser with bandwidth up to 22 GHz makes probing in confined areas easy.

Superior Probe Impedance Minimizes Circuit Loading

Circuit and signal loading is reduced by more than 50% with WaveLink high bandwidth probes compared to competitive probes. In the mid-band frequency range, the difference is even more apparent.

Superior Signal Fidelity and Lowest Noise

WaveLink has exceptional noise performance. In fact, the combination of the probe and the oscilloscope results in measurement performance that is nearly identical to that of a cable input.



D2505-A-PS 25 GHz probe system with Solder-In lead and browser positioner tip.

	D1305-A, D1305-A-PS	D1605-A, D1605-A-PS	D2005-A, D2005-A-PS	D2505-A, D2505-A-PS			
Bandwidth	Dxx05-SI and Dxx05-PT Tips 13 GHz	Dxx05-SI and Dxx05-PT Tips 16 GHz	Dxx05-SI and Dxx05-PT Tips 20 GHz	Dxx05-SI Lead 25 GHz Dxx05-PT Tip 22 GHz typical 20 GHz guaranteed			
Rise Time (10-90%)	Dxx05-SI and Dxx05-PT Tips 32.5 ps (typical)	Dxx05-SI and Dxx05-PT Tips 28 ps (typical)	Dxx05-SI and Dxx05-PT Tips 20 ps (typical)	Dxx05-SI Lead 17.5 ps (typical) Dxx05-PT Tip			
				19 ps (typical)			
Rise Time (20-80%)	Dxx05-SI and Dxx05-PT Tips 24.5 ps (typical)	Dxx05-SI and Dxx05-PT Tips 21 ps (typical)	Dxx05-SI and Dxx05-PT Tips 15 ps (typical)	Dxx05-SI Lead 13 ps (typical) Dxx05-PT Tip 14 ps (typical)			
Noise (Probe)	< 14 nV/√Hz (1.6 mV _{rms}) (typical)	< 14 nV/√Hz (1.8 mV _{rms}) (typical)	< 18 nV/√Hz (2.5 mV _{rms}) (typical)	< 18 nV/√Hz (2.8 mV _{rms}) (typical)			
Input Dynamic Range		2.0 V _{pk-pk} (±1	.0 V) (nominal)				
Input Common Mode Voltage Range		±4 V (r	nominal)				
Input Offset Voltage Range		±2.5 V Differe	ential (nominal)				
Impedance (mid-band, typical)	Dxx05-SI Lead: 300 Ω at 6 GHz, 525 Ω at 13 GHz, 600 Ω at 16 GHz, 300 Ω at 20 GHz, 120 Ω at 25 GHz						

600 Ω at 16 GHz, 300 Ω at 20 GHz, 120 Ω at 25 GHz **Dxx05-PT Tip:** 160 Ω at 6 GHz, 450 Ω at 13 GHz, 240 Ω at 16 GHz, 210 Ω at 20 GHz

SPARQ SIGNAL INTEGRITY NETWORK ANALYZER



network analyzers connect directly to the device under test (DUT) and to PC-based software through a single USB connection for quick, multi-port S-parameter measurements.

SPARQ is the ideal instrument for characterizing multi-port devices common in signal integrity applications at a fraction of the cost of traditional methods. It is ideal for:

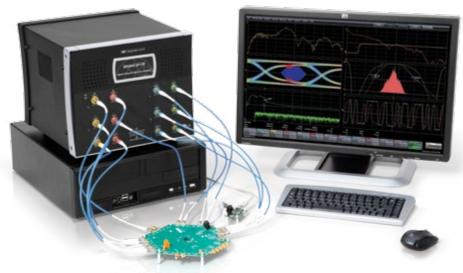
- Development of measurementbased simulation models
- Design validation
- Compliance testing
- High-performance TDR
- PCB testing
- Portable measurement requirements

High-bandwidth, Multi-port S-parameters for the Masses

S-parameter measurements are most often produced by the vector network analyzer (VNA), a difficult instrument that is beyond many budgets. SPARQ is very affordable and simplifies measurements, making S-parameters accessible to all.

PC-based, Small and Portable

Traditional instruments that produce S-parameters are large and fundamentally stationary. The SPARQ, in contrast, is small and weighs less than 20 lbs. It connects to any standard PC through a USB 2.0 interface, allowing SPARQ to run where computing power is easily upgraded.



S-parameters, Quick

VNA measurements begin with the unpleasant and complex task of calibration. This involves multiple connections that can produce misleading results due to operator error. The SPARQ provides calibrated measurements with a single connection to the DUT and offers simple setup choices. Start and complete the entire measurement with a single button press.

Internal Calibration

SPARQ takes a revolutionary approach to calibration by building in calibration standards. This enables measurements to be made without multiple connection steps and removes the need for additional electronic calibration (ECAL) modules. Calibration proceeds quickly without user intervention, so one can calibrate often without resorting to the use of out-of-date saved calibrations.

Characterize Crosstalk with 8 and 12-port SPARQs

Don't just model crosstalk – measure it. With the 8 and 12 port SPARQs, characterize interconnects with two and three differential lanes in order to obtain S-parameters needed for simulations of aggressor/victim/aggressor topologies.

Standard

Math Tools

Display up to 8 math function traces (F1 - F8). The easy-to-use graphical interface simplifies setup of up to two operations on each function trace, and function traces can be chained together to perform math-on-math.

absolute value integral

interpolate (cubic, quadratic, sinx/x) average (summed)

average (continuous) invert (negate) correlation log (base e) (two waveforms) log (base 10) derivative product (x) deskew (resample) ratio (/) difference (-) reciprocal

enhanced resolution rescale (with units) (to 11-bits vertical)

roof envelope sparse exp (base e) square exp (base 10) square root fft (power spectrum, magnitude, sum (+) phase, up to max Mpts) zoom (identity)

Measure Tools

Display any 12 parameters together with statistics, including their average, high, low, and standard deviations. Histicons provide a fast, dynamic view of parameters and wave shape characteristics. Parameter Math allows addition. subtraction, multiplication, or division of two different parameters.

rms

amplitude level @ x area maximum std. deviation base mean top cycles median width data minimum median narrow band phase delay phase

Δ delay narrow band power time @ minimum (min.) duty cycle number of points time @ maximum (max.) duration + overshoot Δ time @ level falltime (90-10%, Δ time @ level overshoot 80-20%, @ level) from trigger peak-to-peak frequency x @ max period first x@min. risetime (10-90%,

last 20-80%, @ level)

Pass/Fail Testing

Simultaneously test multiple parameters against selectable parameter limits or pre-defined masks. Pass or fail conditions can initiate actions including document to local or networked files, e-mail the image of the failure, save waveforms, send a pulse out at the front panel auxiliary BNC output, or (with the GPIB option) send a GPIB SRQ.

Basic Jitter and Timing Analysis Tools

This package provides toolsets for displaying parameter values vs. time, statistical views of parameters using histograms, and persistence view math functions. These tools include:

- "Track" graphs of all parameters, no limitation of number
- · Histograms expanded with 19 histogram parameters and up to 2 billion events

- Cycle-Cycle Jitter - Period @ level - Setup - N-Cycle - Half Period - Hold - Skew - N-Cycle with - Width @ level

start selection - Time Interval - Duty Cycle @ level Frequency @ level Error @ level - Duty Cycle Error

Trend (datalog) of up to 1 million events

- Track graphs of all parameters
- Persistence histogram, persistence (range, sigma)

Standard (cont'd)

Advanced Customization

Provides capability to create a math function or measurement parameter in MATLAB, Excel, C++, JavaScript, or Visual Basic Script (VBS) format and insert it into the oscilloscope's processing stream. All results are processed and displayed on the oscilloscope grid, and are available for further processing. Also permits the creation of customized plug-ins that can be inserted into the scope user interface, control of the scope via Visual Basic scripts embedded in customized functions, and use of Teledyne LeCroy's Custom DSO capabilities.

Software Options

SDAIII Serial Data Analysis Software (LM10Zi-SDAIII) (Included in LM9Zi-SDAIII option, Standard on SDA MCM-Zi-A and DDA MCM-Zi-A Models)

Total Jitter

A complete jitter measurement and analysis toolset with the SDAIII-CompleteLinQ user interface framework. The CompleteLinQ framework provides a single user interface for "LinQ", "Crosstalk", "EyeDrII" and "Virtual Probe" capabilities (purchased separately).

SDAIII provides complete serial data and clock jitter and eye diagram measurement and analysis capabilities. Eye Diagrams with millions of UI are quickly calculated from up to 512 Mpt records, and advanced tools may be used on the Eye Diagram to aid analysis. Complete TIE and Total Jitter (Tj) parameters and analysis functions are provided. Comparison of eye diagrams and jitter analysis between captured lanes and one "reference" location is provided. Includes:

- · Time Interval Error (TIE) Measurement Parameter, Histogram, Spectrum and Jitter Track
- Total Jitter (Tj) Measurement Parameter, Histogram
- Spectrum
- · Eye Diagram Display (sliced)
- · Eye Diagram IsoBER (lines of constant Bit Error Rate)
- · Eye Diagram Mask Violation Locator
- Eye Diagram Measurement Parameters

- Eye Height – Eye Width - Mask hits - One Level - Eye Crossing - Mask out - Zero Level - Avg. Power - Bit Error Rate - Eye Amplitude - Extinction Ratio - Slice Width (setting)

- Q-Fit Tail Representation
- Bathtub Curve
- Cumulative Distribution Function (CDF)
- PLL Track

Jitter Decompostion Models

Three dual-dirac jitter decomposition methods are provided for maximum measurement flexibility. Q-Scale, CDF, Bathtub Curve, and all jitter decomposition measurement parameters can be displayed using any of the three methods.

- Spectral, Rj Direct
- Spectral, Rj+Dj CDF Fit

Random Jitter (Rj) and Non-Data Dependent Jitter (Rj+BUj) Analysis

- · Random Jitter (Rj) Meas Param
- · Rj+BUj Spectrum
- · Periodic Jitter (Pj) Meas Param
- · Rj+BUj Track
- Rj+BUj Histogram
- Pj Inverse FFT

Deterministic Jitter (Dj) Analysis

• Deterministic Jitter (Dj) Measurement Parameter

Software Options (cont'd)

SDAIII Serial Data Analysis Software (continued)

Data Dependent Jitter (DDj) Analysis

- Data Dependent Jitter (DDj) Param
- Duty Cycle Distortion (DCD) Param
- InterSymbol Interference (ISI) Param
- · Digital Pattern display
- DDj Plot (by Pattern or N-bit Sequence)
- DDj Histogram
- ISI Plot (by Pattern)

Reference Lane

 Compare current acquisition to Reference with a side-by-side or single (tabbed) display mode

SDAIII "LinQ" Capability

(SDAIII-LinQ, SDAIII-CrossLinQ, and SDAIII-CompleteLinQ Options)

In addition to all SDAIII capabilities, "LinQ" options includes 4 lanes of simultaneous serial data analysis plus the reference lane. If EyeDrII or VirtualProbe are purchased with SDAIII "LinQ" capability, then those capabilities are provided for all four lanes.

Lanescape Comparison Mode

When multiple lanes are enabled for display, Lanescape Comparison Modes is used. Selections for this mode are as follows:

- · Single: One lane is displayed at a time.
- Dual: Two lanes are selected for display.
- · Mosaic: All enabled lanes are displayed.

SDAIII "Crosstalk" Capability (Included in SDAIII-Crosstalk and SDAIII-CrossLinQ Options)

In addition to all SDAIII capabilities, "Crosstalk" options add the following noise and crosstalk measurements and analysis tools:

- Total, Random and Deterministic noise (Tn, Rn, Dn) measurements
- Breakdown of Dn into InterSymbol Interference noise (ISIn) and Periodic noise (Pn)
- Noise-based eye height and width: EH(BER) and EW(BER)
- Random noise (Rn) + Bounded Uncorrelated noise (BUn) Noise Histogram
- Q-fit for Noise Histogram
- Rn+BUn Noise Spectrum and Peak threshold
- Pn Inverse FFT Plot
- Rn+BUn Noise Track
- · Crosstalk Eye Contour Plot

SDAIII-CompleteLinQ

The ultimate in serial data single or multi-lane link analysis. Provides all the capabilities mentioned above in SDAIII, "LinQ", and "Crosstalk", and also includes EyeDrII and Virtual Probe capabilities.

Eye Doctor II Advanced Signal Integrity Tools (LM10Zi-EYEDRII)

Complete set of channel emulation, de-embedding and receiver equalization simulation tools. Provides capability to emulate a serial data link, de-embed or embed a fixture, cable or serial data channel, add or remove emphasis, and perform CTLE, FFE, or DFE equalization. If purchased with SDAIII, then capabilities are accessed from within the SDAIII-CompleteLinQ user interface framework.

Virtual Probe Signal Integrity Tools (LM10Zi-VIRTUALPROBE)

Provides ability to define a complex serial data channel or topology with up to six circuit elements that may be embedded or de-embedded, allowing "probing" at a location different than the measured position. If purchased with SDAIII and EyeDrII (or with the EYEDRII-VP or CompleteLinQ options), then capabilities are accessed from within the single SDAIII-CompleteLinQ user interface framework.

Software Options (cont'd)

Clock and Clock-Data Timing Jitter Analysis Package (LM10Zi-JITKIT)

Provides convenient setup and four views of jitter (statistical, time, spectrum, and overlaid) for a variety of horizontal, amplitude, and timing parameters. Direct display of jitter measurement values. Supports multiple simultaneous views with fast selection of multiple parameter measurements for fast and easy validation.

Cable De-embedding (LM10Zi-CBL-DE-EMBED)

(Standard on SDA MCM-Zi-A)

Removes cable effects from your measurements. Simply enter the S-parameters or attenuation data of the cable(s) then all of the functionality of the SDA 8 Zi can be utilized with cable effects de-embedded.

8b/10b Decode (LM10Zi-8B10B D)

(Standard on SDA MCM-Zi-A)

Intuitive, color-coded serial decode with powerful search capability enables captured waveforms to be searched for user-defined sequences of symbols. Multi-lane analysis decodes up to four simultaneously captured lanes.

Spectrum Analyzer Mode (LM10Zi-SPECTRUM)

This package provides a new capability to navigate waveforms in the frequency domain using spectrum analyzer type controls. FFT capability added to include:

- · Power averaging
- Power density
- Freq domain parameters
 FFT on up to 128 Meta
- Real and imag components
- FFT on up to 128 Mpts

Disk Drive Measurements Package (LM10Zi-DDM2)

(Standard on DDA MCM-Zi-A)

This package provides disk drive parameter measurements and related mathematical functions for performing disk drive WaveShape Analysis. Disk Drive Parameters are as follows:

- amplitude assymetry
- local base
- local baseline separation
- local maximum
- local minimum
- local number
- local peak-peak
- local time between events
- local time between peaks
- local time between troughs
- local time at minimum
- local time at maximumlocal time peak-trough
- local time over threshold

- local time trough-peak
- local time under threshold
- narrow band phase
- narrow band power
- overwrite
- pulse width 50
- pulse width 50 –
- pulse width 50 +
- resolution
- track average amplitude
- track average amplitude -
- track average amplitude +
- auto-correlation s/n
- non-linear transition shift

LabMaster 10 Zi Series	20 GHz	25 GHz	30 GHz	36 GHz	50 GHz	59 GHz	65 GHz	100 GHz
Vertical System								
Analog Bandwidth					50 GHz	59 GHz	65 GHz	100 GHz
@ 50 Ω (-3 dB)					(≥10 mV/div)	(≥10 mV/div)	(≥10 mV/div)	(≥10 mV/div)
(1.85mm Inputs)	20 GHz	25 GHz	30 GHz			36 GHz		
Analog Bandwidth \bigcirc 50 Ω (-3 dB)						30 GHZ (≥5 mV/div)		
(2.92mm Inputs)	(≥5 mV/div)	(≥5 mV/div)	(≥5 mV/div)			(≥5 111V/UIV)		
Rise Time (10–90%, 50 Ω)	19.3 ps	15.4 ps	12.8 ps	10.7 ps	8.0 ps	6.9 ps	6.5 ps	4.5 ps
(test limit, flatness mode)	13.0 po	. σ ρσ	12.0 μο	po	σ.σ ρσ	υ.5 ρυ	σ.σ ρσ	σ ρσ
Rise Time $(20-80\%, 50 \Omega)$ (flatness mode)	14.5 ps	11.6 ps	9.6 ps	8.0 ps	6.0 ps	5.2 ps	4.9 ps	3.5 ps
Input Channels	Up to 8	0, depending on	configuration se	elected.	Up to 4	0, depending on	configuration s	elected.
<u> </u>			30 2.92mm inpu			Up to 80 (
Bandwidth Limiters	1 GHz,	1 GHz,	1 GHz,	1 GHz,	For ≤ 36 GHz	For ≤ 36 GHz	For ≤ 36 G	Hz Mode:
	3 GHz,	3 GHz,	3 GHz,	3 GHz,	Mode:	Mode:	1 GHz,	3 GHz,
	4 GHz,	4 GHz,	4 GHz,	4 GHz,	1 GHz, 3 GHz,	1 GHz, 3 GHz,		6 GHz,
	6 GHz,	6 GHz,	6 GHz,	6 GHz,	4 GHz, 6 GHz,	4 GHz, 6 GHz,		13 GHz,
	8 GHz,	8 GHz,	8 GHz,	8 GHz,	8 GHz,	8 GHz,		20 GHz
	13 GHz,	13 GHz,	13 GHz,	13 GHz,	13 GHz,	13 GHz,		GHz 33 GHz
	16 GHz	16 GHz	16 GHz	16 GHz	16 GHz,	16 GHz,		Hz Mode:
	10 0112	20 GHz	20 GHz	20 GHz	20 GHz	20 GHz	50 GHz	60 GHz
		20 0112	25 GHz	25 GHz	25 GHz,	25 GHz,		
			23 01 12	30 GHz	30 GHz, 33	30 GHz,		
					GHz	33 GHz		
				33 GHz	For > 36 GHz	For > 36 GHz		
					Mode: None	Mode:		
Input Impedance		2 02mm Inni	uts: 50 Ω ±2%			50 GHz	uts: 50 Ω ±2%	
input impedance		2.92mm mpc	115. 00 \$2 12 %				uts: 50 Ω ±2%	
					1mn		2% (10-100 Zi-A	only)
Input Coupling		2 92 mm Innuts	s: 50 Ω: DC, GND				: 50 Ω: DC, GNE	
input ooupling		2.32 mm mpate	. 00 12. 00, 0110			•	uts: 50 Ω: DC	
					1 mr		C (10-100 Zi-A d	vnlv)
Maximum Input Voltage		2 92 mn	n Inputs:		11111		n Inputs:	or iry)
maximam input vertuge	±2 Vma		, 5.5V _{rms} @ ≥76	mV/div			<76 mV/div,	
			7 - 111130	, -			≥76 mV/div	
					1.85		Vmax @ ≤80 m	V/div
							0 mV/div (10-10	
Channel-Channel Isolation		DC to 36 GHz:	60 dB (>1000:1)			6 GHz : 60 dB (>		NA
			nm input channe	ale		o 2.92mm inpu		
			div settings, typ			erent v/div setti		
	00.1		a., ootago, typ			5 GHz : 40 dB (
						o 1.85mm inpu		
					same or diff	erent v/div setti	ings, typical)	
			9 hite: up t	4 4 1 2 2 2 1		: (EDEO)		
Vertical Resolution		,	o bits, up t	<u>o II bits with e</u>	nhanced resolut	ion (ERES)		
Vertical Resolution Sensitivity			.92mm):			50 Ω (2.	.92mm):	
		5 mV-500mV/d	. 92mm) : div, fully variable			50 Ω (2 .5 mV-500mV/c	div, fully variable	
		5 mV-500mV/d	.92mm):			50 Ω (2 .5 mV-500mV/d (5-9.9 mV/d	div, fully variable liv via zoom)	
		5 mV-500mV/d	. 92mm) : div, fully variable			50 Ω (2 .5 mV-500mV/d (5-9.9 mV/d 50 Ω (1.85	div, fully variable liv via zoom) mm, 1 mm) :	
		5 mV-500mV/d	. 92mm) : div, fully variable			50 Ω (2 .5 mV-500mV/d (5-9.9 mV/d 50 Ω (1.85 .10 mV-80mV/d	div, fully variable liv via zoom) mm, 1mm): div, fully variable	
		5 mV-500mV/d	. 92mm) : div, fully variable			50 Ω (2 5 mV-500mV/d (5-9.9 mV/d 50 Ω (1.85 10 mV-80mV/d gain settings p	div, fully variable liv via zoom) mm, 1mm): div, fully variable ossible through	
Sensitivity		5 mV-500mV/d (5-9.9 mV/d	. 92mm): div, fully variable liv via zoom)		Higher	50 Ω (2. 5 mV-500mV/d (5-9.9 mV/d 50 Ω (1.85 10 mV-80mV/d gain settings p external at	div, fully variable liv via zoom) mm, 1mm): div, fully variable ossible through ttenuators.	
Sensitivity DC Vertical Gain Accuracy		5 mV-500mV/d (5-9.9 mV/d	. 92mm): div, fully variable liv via zoom)			50 Ω (2. 5 mV-500mV/d (5-9.9 mV/d 50 Ω (1.85 10 mV-80mV/d gain settings p external at	div, fully variable liv via zoom) mm, 1mm): div, fully variable ossible through ttenuators.	
DC Vertical Gain Accuracy (Gain Component of		5 mV-500mV/d (5-9.9 mV/d	. 92mm): div, fully variable liv via zoom)		Higher	50 Ω (2. 5 mV-500mV/d (5-9.9 mV/d 50 Ω (1.85 10 mV-80mV/d gain settings p external at	div, fully variable liv via zoom) mm, 1mm): div, fully variable ossible through ttenuators.	
DC Vertical Gain Accuracy (Gain Component of DC Accuracy)		5 mV-500mV/d (5-9.9 mV/d	.92mm): div, fully variable liv via zoom) ±1% F.S. (typical)	ı, offset at 0V; ±	Higher 1.5% F.S. (test lin	50 Ω (2. 5 mV-500mV/α (5-9.9 mV/d 50 Ω (1.85. 10 mV-80mV/α gain settings p external at mit), offset at 0°	div, fully variable liv via zoom) mm, 1mm): div, fully variable ossible through ttenuators.	use of
DC Vertical Gain Accuracy (Gain Component of DC Accuracy) Vertical Noise Floor	1.39 mV _{rms}	5 mV-500mV/d (5-9.9 mV/d	.92mm): div, fully variable liv via zoom) ±1% F.S. (typical)	, offset at 0V; ± 1.88 mV _{rms}	Higher 1.5% F.S. (test lin 3.1 mV _{rms}	50 Ω (2.5 mV-500mV/α (5-9.9 mV/α (5-9.9 mV/α 50 Ω (1.85 10 mV-80mV/α gain settings pexternal at mit), offset at 0 0 3.7 mV _{rms}	div, fully variable liv via zoom) mm, 1mm): div, fully variable ossible through ttenuators. V 3.9 mV _{rms}	use of
DC Vertical Gain Accuracy (Gain Component of DC Accuracy) Vertical Noise Floor (50 mV/div)		5 mV-500mV/d (5-9.9 mV/d : : : 1.57 mV _{rms} (typical)	.92mm): div, fully variable liv via zoom) ±1% F.S. (typical) 1.69 mV _{rms} (typical)	ı, offset at 0V; ±	Higher 1.5% F.S. (test lin	50 Ω (2.5 mV-500mV/α (5-9.9 mV/α 50 Ω (1.85 10 mV-80mV/α gain settings p external at mit), offset at 0 0 3.7 mV _{rms} (typical)	div, fully variable liv via zoom) mm, 1mm): div, fully variable ossible through ttenuators. 3.9 mV _{rms} (typical)	use of
DC Vertical Gain Accuracy (Gain Component of DC Accuracy) Vertical Noise Floor	1.39 mV _{rms}	5 mV-500mV/d (5-9.9 mV/d :: 1.57 mV _{rms} (typical)	.92mm): div, fully variable liv via zoom) ±1% F.S. (typical) 1.69 mV _{rms} (typical)	, offset at 0V; ± 1.88 mV _{rms}	Higher 1.5% F.S. (test lin 3.1 mV _{rms}	50 Ω (2.5 mV-500mV/c (5-9.9 mV/d) 50 Ω (1.85 to mV-80mV/c gain settings p external at mit), offset at 0 to mV/c (typical)	div, fully variable liv via zoom) mm, 1mm): div, fully variable ossible through ttenuators. 3.9 mV _{rms} (typical)	use of
DC Vertical Gain Accuracy (Gain Component of DC Accuracy) Vertical Noise Floor (50 mV/div)	1.39 mV _{rms}	5 mV-500mV/d (5-9.9 mV/d 1.57 mV _{rms} (typical) 50 ±500 mV @	.92mm): div, fully variable liv via zoom) ±1% F.S. (typical) 1.69 mV _{rms} (typical) Ω: 5-75 mV/div	, offset at 0V; ± 1.88 mV _{rms}	Higher 1.5% F.S. (test lin 3.1 mV _{rms}	50 Ω (2.5 mV-500mV/α (5-9.9 mV/α (5-9.9 mV/α 50 Ω (1.85 10 mV-80mV/α gain settings p external at mit), offset at 0 0 3.7 mV _{rms} (typical) 50 Ω (2. ±500 mV @	div, fully variable liv via zoom) mm, 1mm): div, fully variable ossible through ttenuators. 3.9 mV _{rms} (typical) 92mm): 5-75 mV/div	use of
DC Vertical Gain Accuracy (Gain Component of DC Accuracy) Vertical Noise Floor (50 mV/div)	1.39 mV _{rms}	5 mV-500mV/d (5-9.9 mV/d 1.57 mV _{rms} (typical) 50 ±500 mV @	.92mm): div, fully variable liv via zoom) ±1% F.S. (typical) 1.69 mV _{rms} (typical)	, offset at 0V; ± 1.88 mV _{rms}	Higher 1.5% F.S. (test lin 3.1 mV _{rms}	50 Ω (2.5 mV-500mV/c (5-9.9 mV/d) 50 Ω (1.85 10 mV-80mV/c gain settings p external at mit), offset at 0 v (1.2 mit) 3.7 mV _{rms} (typical) 50 Ω (2.2 ±500 mV @ ±4 V @ 76 mV/c	div, fully variable liv via zoom) mm, 1mm): div, fully variable ossible through ttenuators. 3.9 mV _{rms} (typical) 92mm): 5-75 mV/div div -500mV/div	use of
DC Vertical Gain Accuracy (Gain Component of DC Accuracy) Vertical Noise Floor (50 mV/div)	1.39 mV _{rms}	5 mV-500mV/d (5-9.9 mV/d 1.57 mV _{rms} (typical) 50 ±500 mV @	.92mm): div, fully variable liv via zoom) ±1% F.S. (typical) 1.69 mV _{rms} (typical) Ω: 5-75 mV/div	, offset at 0V; ± 1.88 mV _{rms}	Higher 1.5% F.S. (test lin 3.1 mV _{rms}	50 Ω (2.5 mV-500mV/c (5-9.9 mV/d) 50 Ω (1.85 10 mV-80mV/c gain settings p external at mit), offset at 0 10 mV/ms (typical) 50 Ω (2. ±500 mV @ ±4 V @ 76 mV/50 Ω (1.85	div, fully variable liv via zoom) mm, 1mm): div, fully variable ossible through ttenuators. 3.9 mV _{rms} (typical) 92mm): 5-75 mV/div	use of

LabMaster 10 Zi Series	20 GHz	25 GHz	30 GHz	36 GHz	50 GHz	59 GHz	65 GHz	100 GHz
Horizontal System								
Timebases			e with 10 GHz cl					
	10 G		r all channels en entical to that pi					all
ime/Division Range	10 ps/div-256 s				Sirigic, convent	For >36 G		
·	minimum sample	e rate of 200	kS/s and install	led memory).		10 ps/div -		
					(maxim	um capture time		160 GS/s
	and installed memory). For ≤36 GHz Mode:							
	10 ps/div-256 s/div (maximum capture time is							
					minimum sar	mple rate of 200	kS/s and insta	alled memory)
Clock Accuracy					om/yr from last			
Sample Clock Jitter					uired Time Rang mebase Referer			
					imebase Referer			
					uired Time Rang			
					imebase Refere			
			130f	s _{rms} (External 1	<u>imebase Refere</u>	nce)		
Delta Time Measurement			Noise \\^2 +					
Accuracy	^	√2 * (-	SlewRate +	(Sample Clock	k Jitter _{rms})² + (clock accuracy	* reading)	
Catan Management Elemen								
Jitter Measurement Floor		17	Noise \setminus^2	(0 1 0)				
		/ (-	$\frac{Noise}{SlewRate}$ +	(Sample Clock	(Jitter _{rms})²			
1'11 D 1 Ol 1		, ,				1500	10	0.5
litter Between Channels Measured at maximum		<250	rs _{rms}		<190fs _{rms}	<150fs _{rms}	<13	Ofs _{rms}
pandwidth)								
Frigger and Interpolator		<	0.1 ps _{rms} (typical	al, software ass	isted), 2 ps _{rms} (t	ypical, hardware	<u>e)</u>	
Jitter Channel-Channel Deskew			tipo o /div. o ottip	a or OF no mov	(which over in In	raar) aaab abar	an al	
Snannel-Channel Deskew Range		±9 x	k time/div. settin	ig or 25 hs max.	. (whichever is ia	rger), each char	inei	
External Timebase		10 MHz; 50	Ω impedance, a	applied at the re	ear input of MCM	1-Zi Master Cont	rol Module	,
Reference (Input)								
External Timebase Reference (Output)		10 MHz	; 50 Ω impedand	ce, output at the	rear of MCM-Zi	Master Control	Module	
reference (Output)								
		30 GS/s on e	each channel.			/s on each chan		
Acquisition System Single-Shot Sample Rate/Ch	3	30 GS/s on e	ach channel.		160 GS	S/s on each cha	nnel in >36 GH	z Mode.
Single-Shot Sample Rate/Ch	{			orms/second (in	160 GS 240	S/s on each char GS/s on 100 GH	nnel in >36 GH Iz (10-100 Zi- <i>A</i>	z Mode.
Single-Shot Sample Rate/Ch Maximum Trigger Rate			each channel. 000,000 wavefo	,	160 GS 240	S/s on each char GS/s on 100 GH	nnel in >36 GH Iz (10-100 Zi- <i>A</i>	z Mode.
Single-Shot Sample Rate/Ch Maximum Trigger Rate Intersegment Time Maximum Acquisition	3		000,000 wavefo	,	160 GS 240 Sequence Mode µs	S/s on each char GS/s on 100 GH	nnel in >36 GH Iz (10-100 Zi-A !ls)	z Mode. (only) 1536 Mpts
Single-Shot Sample Rate/Ch Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory	{	1,(000,000 wavefo pts/Ch	1	160 GS 240 Sequence Mode µs 1024 Mp	6/s on each char GS/s on 100 GH c, up to 4 channe ots/Ch (2 Ch ope	nnel in >36 GH Iz (10-100 Zi-A !ls)	z Mode. (only)
Single-Shot Sample Rate/Ch Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory		1,(000,000 wavefo pts/Ch	1 Option (See belo	160 GS 240 Sequence Mode µs	6/s on each char GS/s on 100 GH c, up to 4 channe ots/Ch (2 Ch ope	nnel in >36 GH Iz (10-100 Zi-A :ls)	z Mode. conly) 1536 Mpts
Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory (Number of Segments)	\{	1,(000,000 wavefo pts/Ch	1 Option (See belo	160 GS 240 Sequence Mode µs 1024 Mp	6/s on each char GS/s on 100 GH , up to 4 channe ots/Ch (2 Ch ope memory length)	nnel in >36 GH Iz (10-100 Zi-A :ls)	z Mode. conly) 1536 Mpts
Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory (Number of Segments)	\$-32	1,(512 M _l	000,000 wavefo pts/Ch S-32 Memory C	Option (See belo	160 GS 240 Sequence Mode µs 1024 Mp w for details on (500)	6/s on each char GS/s on 100 GH , up to 4 channe ots/Ch (2 Ch ope memory length)	nnel in >36 GH Iz (10-100 Zi-A Is) eration)	z Mode. conly) 1536 Mpts
Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory (Number of Segments)		1,(512 M _l	000,000 wavefo pts/Ch S-32 Memory C ≤ 36 GHz/Ch	Dption (See belo (3,5	160 GS 240 Sequence Mode µs 1024 Mp w for details on 500) 100 GHz	6/s on each chai GS/s on 100 GH , up to 4 channe ots/Ch (2 Ch ope memory length) Number	nnel in >36 GH Iz (10-100 Zi-A eration) Segments	z Mode. conly) 1536 Mpts
Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory (Number of Segments)	S-32	1,(512 M) 2 4	000,000 wavefo pts/Ch S-32 Memory C ≤ 36 GHz/Ch 32 Mpts	Dption (See belo (3,5 50-65 GHz 64 Mpts	160 GS 240 Sequence Mode µs 1024 Mp w for details on (500) 100 GHz 96 Mpts	6/s on each chai GS/s on 100 GH , up to 4 channe ots/Ch (2 Ch ope memory length) Number	nnel in >36 GH lz (10-100 Zi-A eration) Segments ,500 ,500	z Mode. conly) 1536 Mpts
Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory (Number of Segments)	S-32 M-6 ² L-12:	1,0 512 Mp 2 4	000,000 wavefo pts/Ch S-32 Memory C ≤ 36 GHz/Ch 32 Mpts 64 Mpts 128 Mpts	Dption (See belo (3,4 50-65 GHz 64 Mpts 128 Mpts 256 Mpts	160 GS 240 Sequence Mode µs 1024 Mp w for details on (500) 100 GHz 96 Mpts 192 Mpts 384 Mpts	6/s on each char GS/s on 100 GHz, up to 4 channel ots/Ch (2 Ch ope memory length) Number 3 7	nnel in >36 GH lz (10-100 Zi-A eration) Segments ,500 ,500	z Mode. conly) 1536 Mpts
Single-Shot Sample Rate/Ch Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory	S-32 M-64 L-12 VL-2	1,0 512 Mp 2 4 28 256	000,000 wavefo pts/Ch S-32 Memory C ≤ 36 GHz/Ch 32 Mpts 64 Mpts 128 Mpts 256 Mpts	Dption (See belo (3,8) 50-65 GHz 64 Mpts 128 Mpts 256 Mpts 512 Mpts	Sequence Mode µs 1024 Mp w for details on (500) 100 GHz 96 Mpts 192 Mpts 384 Mpts 768 Mpts	S/s on each char GS/s on 100 GHz, up to 4 channel ots/Ch (2 Ch ope memory length) Number 3 7 15	nnel in >36 GH lz (10-100 Zi-A lz) pration) Segments ,500 ,500 5,000	z Mode. conly) 1536 Mpts
Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory (Number of Segments)	S-32 M-6 ² L-12:	1,0 512 Mp 2 4 28 256	000,000 wavefo pts/Ch S-32 Memory C ≤ 36 GHz/Ch 32 Mpts 64 Mpts 128 Mpts	Dption (See belo (3,4 50-65 GHz 64 Mpts 128 Mpts 256 Mpts	160 GS 240 Sequence Mode µs 1024 Mp w for details on (500) 100 GHz 96 Mpts 192 Mpts 384 Mpts	S/s on each char GS/s on 100 GHz, up to 4 channel ots/Ch (2 Ch ope memory length) Number 3 7 15	nnel in >36 GH lz (10-100 Zi-A eration) Segments ,500 ,500	z Mode. conly) 1536 Mpt
Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory (Number of Segments) Memory Options	S-32 M-64 L-12 VL-2	1,0 512 Mp 2 4 4 28 256 512	000,000 wavefo pts/Ch S-32 Memory C ≤ 36 GHz/Ch 32 Mpts 64 Mpts 128 Mpts 256 Mpts 512 Mpts	Dption (See belo (3, 50-65 GHz 64 Mpts 128 Mpts 256 Mpts 512 Mpts 1024 Mpts	160 GS 240 Sequence Mode µs 1024 Mp w for details on (500) 100 GHz 96 Mpts 192 Mpts 384 Mpts 768 Mpts 1536 Mpts	S/s on each chain GS/s on 100 GHz, up to 4 channel ots/Ch (2 Ch opermemory length) Number 3 7 15	nnel in >36 GH lz (10-100 Zi-A ls) ration) Segments ,500 ,500 5,000 5,000	z Mode. conly) 1536 Mpts
Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory (Number of Segments) Memory Options Acquisition Processing Averaging	S-32 M-64 L-12 VL-2	1,0 512 Mp 2 4 4 28 256 512	ooo,000 wavefo pts/Ch S-32 Memory C ≤ 36 GHz/Ch 32 Mpts 64 Mpts 128 Mpts 256 Mpts 512 Mpts averaging to 1 r	Dption (See belo (3,) 50-65 GHz 64 Mpts 128 Mpts 256 Mpts 512 Mpts 1024 Mpts	Sequence Mode µs 1024 Mp w for details on (500) 100 GHz 96 Mpts 192 Mpts 384 Mpts 768 Mpts 1536 Mpts	S/s on each chained of the second of the sec	nnel in >36 GH lz (10-100 Zi-A ls) ration) Segments ,500 ,500 5,000 5,000	z Mode. conly) 1536 Mpts
Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory (Number of Segments) Memory Options Acquisition Processing	S-32 M-64 L-12 VL-2	1,0 512 Mp 2 4 4 28 256 512	000,000 wavefo pts/Ch S-32 Memory C ≤ 36 GHz/Ch 32 Mpts 64 Mpts 128 Mpts 256 Mpts 512 Mpts averaging to 1 r Fro	Dption (See belo (3,) 50-65 GHz 64 Mpts 128 Mpts 256 Mpts 512 Mpts 1024 Mpts	160 GS 240 Sequence Mode µs 1024 Mp w for details on (500) 100 GHz 96 Mpts 192 Mpts 384 Mpts 768 Mpts 1536 Mpts	S/s on each chained of the second of the sec	nnel in >36 GH lz (10-100 Zi-A ls) ration) Segments ,500 ,500 5,000 5,000	z Mode. (only) 1536 Mpts

Normal_Auto_Single_and Stop	LabMaster 10 Zi Series	20 GHz	25 GHz	30 GHz	36 GHz	50 GHz	59 GHz	65 GHz	100 GHz	
Any Ch 1 4 (Fitge, Window, SMART, Cascade triggers), AUX, Internal Fast Edge, or any input channel (Edge trigger only), ditional 10xx2 Acquasition Modules (Channels 5 and higher). Coupling Mode DD CA, CHEHR, LERBI Pret trigger Delay D-100X of memory size, ediptistable in 1% increments of 100 ms). Post-trigger Delay D-100X of memory size, ediptistable in 1% increments of 100 ms). Post-trigger Delay D-100X of memory size, ediptistable in 1% increments of 100 ms). Post-trigger Delay D-100X of memory size, ediptistable in 1% increments of 100 ms). Post-trigger Polay From 2 ms up to 20 s or from 1 to 99 999 999 weets Internal Trigger Reade 1		Normal Auto Single and Stop								
Coupling Mode DC, AC, HFRei, LFRei Pretragger Delay 0 - 10,00% of memory size adjustable in 18, increments of 100 ns) Post trigger Delay 0 - 10,000 divisions in real time mode, limited at slower time/div settings Hold off by Time or Events From 2 ns up to 20 os from 1 to 9,999,999 events Internal Trigger Renge Trigger Sensitivity with For Ch 1-80 of a Labbasser 10 21 system: 3 div @ -12 6Hz 1 5 div @ -8 6Hz (185/2 92mm inputs) External Trigger Sensitivity, For Ch 1-4 only of any Labbasser 10 20 system: 1 5 div @ -8 6Hz (10 div @ -8 6Hz (10 div @ -8 6Hz) (10		Any Ch 1-4 (Edge	, Window, SM		riggers), AUX, int	ernal Fast Edge;		annel (Edge trig	ger only) on ac	
Pre-trigger Delay				Slope and le			t line trigger.			
Post-trigger Delay 1-10,000 divisions in real time mode, limited at slower time/div settings From 2 ns ub to 20 so r from 11 on 9939-939-99 events Internal Trigger Frange 1-4.1 div from center Trigger Sensitivity with For Ch 1-8.0 of a LabMaster 10 27 system: 1.6 div @ -8 0 Hz 1.0 div @ -5 0 Hz 1.6 div @ -8 0 Hz 1.0 div @ -5 Hz 1.0 div @ -5 0 Hz 1.0 div @ -5										
Hold off by Time or Events From 2 ns up to 20 s or from 1 to 99,999,999 events Internel Trigger Range H. 1. Link from center Frigger Sensitivity with Edge Trigger (1.85/2.92mm Inputs) For Ch 1-80 of a LabMaster 10 Zi system: Edge Trigger (1.85/2.92mm Inputs) L. S. div @ 48 GHz L. S. div @ 45 GHz H. S. div @ 45 GHz H										
Internal Trigger Bange 14.1 (div from center Trigger Sensitivity with For Ch 1.8 of a LabMaster 10 Zi ysystem: 5 (1.857 29.mm Inputs) 1.5 (div @ -6 5 Chz (1.857 29.mm Inputs) External Trigger Sensitivity, For Ch 1.4 only of any LabMaster 10 Zi ysystem: (Edge Trigger) External Trigger Sensitivity, For Ch 1.4 only of any LabMaster 10 Zi			0-1					tings		
Trigger Sensitivity, with Edge Triggers (1.85/2.92mm Inputs) 1. 5. div @ 4.8 GHz 1. 6. div @ 4.5 GHz 1. 6				From 2 ns			99 events			
External Trigger Sensitivity. (In 85/2 92mm Inputs) External Trigger Sensitivity. For Ch 1-4 only of any LathMaster 10xx 21 Acquisition Module: 2 driw @ -6 Ghtz (for DC couplings 3 10 mW/dis 90 g) External Trigger Sensitivity. For Ch 1-4 only of any LathMaster 10xx 21 Acquisition Module: 2 driw @ -6 Ghtz 1.0 driw @ -6 Ghtz 2 driw @ -6 Ghtz 1.0 driw				For			tom:			
(1.85/2.92mm Inputs) 1. 5 div @ -8 GHz (for DC coupling. ≥ 10 mW/div. 50 Ω) External Trigger Sensitivity, (Fidge Trigger) For Ch 1-4 only of any LabMaster 10xx-21 Acquisition Module: 2. 0 div @ -1 GbW Mizz, 1. 5 div @ -8 GHz, 1. 5 div @				FOL			sterri.			
External Trigger Sensitivity, [For Ch 1-4 only of any LabMaster 10xx-2f Acquisition Module: 2 drw @ -1 GHz, 1.5 drw @ -5 GM MHz, 1.0 drw @ -2 GM MHz, 1.5 drw @ -5 GW MHz, 1.5 drw MHz,										
External Trigger Sensitivity, For Ch 1-4 only of any LabMaster 10xx2 Acquisition Module: 2 div @ -1 Cht2. 2 div @ < 2 00 MHz. 1.0 div @ < 200 MHz. 1.0 div	(1.65/2.9211111 IIIputs)									
External Trigger Sensitivity, (Edge Trigger) 2 div Ø o 1 GHz 1.5 div Ø o ≤ 500 MHz 1.0 div Ø o ≤ 200 MHz 1.6 div Ø o ≤ 500 MHz 1.7 div Ø o ≤ 200 MHz 1.7 div Ø o ≤ 200 MHz 1.8 div Ø o ≤ 500 MHz 1.				//		•	2)			
2 div @ < 1 GHz.	Futamal Trianan Canaiti itu									
1.5 div @ < 500 MHz, 1.0 div @ < 200 MHz, 1.0 div @ < 200 MHz, 1.0 div @ < 200 MHz, (for DC coupling) Max. Trigger Frequency, SIMART Trigger 2.0 GHz @ ≥ 10 mV/div (minimum triggerable width 200 ps) External Trigger Input For any LabMaster 10xx-21 Acquisition Module: Aux (±0.4 v) Range ((hy) Ch1-4 Acquisition Module hav ±ch2 Avx (±0.4 v) Range ((hy) Ch1-4 Acquisition Module hav ±ch2 Avx (±0.4 v) Range ((hy) Ch1-4 Acquisition Module hav ±ch2 Avx (±0.4 v) Range ((hy) Ch1-4 Acquisition Module hav ±ch2 Avx (±0.4 v) Range ((hy) Ch1-4 Acquisition Module hav ±ch2 Avx (±0.4 v) Range ((hy) Ch1-4 Acquisition Module hav ±ch2 Avx (±0.4 v) Range ((hy) Ch1-4 Acquisition Module hav ±ch2 Avx (±0.4 v) Range ((hy) Ch1-4 Acquisition Module have ±ch2 Avx (±0.4 v) Rangers'' State or Edge Qualified Triggers on any input source only if a defined state or edge occurred on another input source. Holdoff between sources is selectable by time or events the first segment of the acquisition. Holdoff between sources is selectable by time or events the first segment of the acquisition. Holdoff between sources is selectable by time or events Triggers in signal drops out for longer than selected time betwen 1 ns and 20 s Pattern Logic combination (AND, NAND, OR, NOR) of 5 inputs (4 channels and external trigger input). Each source can be high, I don't care. The High and Low level can be selected independently. Triggers at start or end of the pattern SIMART Triggers with Exclusion Technology Glitch Triggers on positive or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults. Width (Signal or Pattern) Triggers on positive, negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults. Triggers on positive, or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults. Triggers on positive, or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults. Triggers on positive, or negative glitch				For Cn 1-4 only			isition Module:			
1.0 of w @ < 200 MHz,	(Edge Trigger)									
Max. Trigger Frequency, SMART Trigger Por Ch 1-4 of a LabMaster 10x-21 Acquisition Module: SMART Trigger (Only Ch 1-4 Day 2 Acquisition Module Aux (24 dV) Range (Only Ch 1-4 Acquisition Module has "active" AUX Input) Basic Triggers Basic Triggers Triggers when signal meets slope (positive, negative, or either) and level condition. Window Triggers when signal meets slope (positive, negative, or either) and level condition. Window Triggers when signal meets slope (positive, negative, or either) and level condition. Window Triggers on any input source only if a defined state or edge occurred on another input source. Holdoff between sources is selectable by time or events Qualified First In Sequence acquisition mode, triggers repeatably on event B only if a defined pattern, state, or edge (event A) is satisf the first segment of the acquisition. Holdoff between sources is selectable by time or events Dropout Triggers if signal drops out for longer than selected time between 1 ns and 20 s Pattern Logic combination (ARD, NAND, OR, NOR) of 5 inputs (d channels and external parin junt). Each source can be high, I don't care. The High and Low level can be selected independently. Triggers at start or end of the pattern SMART Triggers with Exclusion Technology Glitch Triggers on positive or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive, negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive or negative unto defined by two voltage limits and two time limits. Select between 1 ns and 20 s Trigger on edge rates. Select limits for dV, dt, and slope. Select edge limits between 1 ns and 20 ns Trigger on edge rates. Select limits for dV, dt, and slope. Select edge limits between 1 ns and 20 ns Trigger on edge rates. Select limits for dV, dt, and slope. Select edge limits between 1 ns and 20 ns Trigger on intermittent faults by specifying the expected behavior and triggering when										
Max Trigger Frequency, SAMART Triggers 2.0 GHz @ 10 Myddw (minimum triggerable width 200 ps) External Trigger Input Range (Only Ch1-4 Acquisition Module: Aux (±0.4 V) Range (Only Ch1-4 Acquisition Module: Aux (±0.4 V) Range Rasic Triggers Edge Triggers when signal meets slope (positive, negative, or either) and level condition. Window Triggers when signal exits a window defined by adjustable thresholds SMART Triggers* State or Edge Qualified Triggers on any input source only if a defined state or edge occurred on another input source. Holdoff between sources is selectable by time or events In Sequence acquisition mode, triggers repeatably on event B only if a defined pattern, state, or edge (event A) is satisf the first segment of the acquisition. Holdoff between sources is selectable by time or events Dropout Triggers if signal drops out for longer than selected time where I ns and 20 s Pattern Logic combination (AND, NAND, OR, NOR) of 5 inputs (4 channels and external trigger input). Each source can be high, if don't care. The High and Low level can be selected independently. Triggers at start or end of the pattern SMART Triggers with Exclusion Technology Glitch Triggers on positive or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults. Width (Signal or Pattern) Triggers on positive, negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults. Width (Signal or Pattern) Triggers on any source if a given state (or transition edge) has occurred on another source. Delay between sources is 1 ns to 20 s, or 10 to 99,999 999 events Trigger on positive or negative units defined by two voltager limits and two time limits. Select between 1 ns and 20 ns Exclusion Triggering Cascade A then B then C (Measurement. Logic) Width, Glitch, Interval, Dropout, or Measurement. Measurement can to Stage B only. Cascade A then B then C then D Edge, Window, Pattern (Logic), Width, Glitch, Interval, Dropout, or Measurement. Measurement can be o										
SMART Trigger (nput For any LabMaster 10x:21 Acquisition Module: Aux (±0.4 V) Range (Only Ch1-4 Acquisition Module has "active" AUX Input) Basic Triggers Triggers when signal meets slope (positive, negative, or either) and level condition. Window Triggers when signal meets slope (positive, negative, or either) and level condition. Window Triggers when signal exits a window defined by adjustable thresholds SMART Triggers" State or Edge Qualified Triggers on any input source only if a defined state or edge occurred on another input source. Holdoff between sources is selectable by time or events Qualified First In Sequence acquisition mode, triggers repeatably on event B only if a defined pattern, state, or edge (event A) is satisf the first segment of the acquisition. Holdoff between sources is selectable by time or events Dropout Triggers if signal drops out for longer than selected time between 1 ns and 20 s Pattern Logic combination (AND, NAND, OP, NOR) of inputs (4 channels and extern lirgger input). Each source can be high, I don't care. The High and Low level can be selected independently. Triggers at start or end of the pattern Triggers with Exclusion Technology Glitch Triggers on positive or negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults with the selectable as low as 200ps to 20 s, or on intermittent faults interval (Signal or Pattern) Triggers on positive or negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults interval (Signal or Pattern) Triggers on positive or negative or negative in the visit of the selectable as low as 200ps to 20 s, or on intermittent faults interval (Signal or Pattern) Triggers on any source if a given state (or transition edge) has occurred on another source. Delay between sources is 1 ns to 20 s, or 1 to 99,999 events Trigger on positive or negative units defined by two ovidage limits and two pure limits. Select between 1 ns and 20 ns Trigger on intermittent faults by spec	May Trigger Frequency			For Ch 1-4			on Module.			
External Trigger Input Range (Only Ch1-4 Acquisition Module: Aux (£04 V) Range (Only Ch1-4 Acquisition Module has "active" AUX Input) Basic Triggers Edge Triggers when signal meets slope (positive, negative, or either) and level condition. Window Triggers when signal exits a window defined by adjustable thresholds SMART Triggers" State or Edge Qualified Triggers on any input source only if a defined state or edge occurred on another input source. Holdoff between sources is selectable by time or events Qualified First In Sequence acquisition mode, triggers repeatably on event B only if a defined pattern, state, or edge (event A) is satisf the first segment of the acquisition. Holdoff between sources is selectable by time or events Triggers (signal drops out for longer than selected the between I na and 20 s Pattern Logic combination (AND, NAND, OR, NOR) of 5 inputs (4 channels and external trigger input). Each source can be high, I don't care. The High and Low level can be selected independently. Triggers at start or end of the pattern SMART Triggers with Exclusion Technology Glitch Triggers on positive or negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent fault Interval (Signal or Pattern) Interval (Signal or Pattern) Triggers on any source if a given state (or transition edge) has occurred on another source. Delay between sources is 1 ns to 2, s, or 1 to 99,999,999 events Runt Trigger on positive or negative units defined by two voltage limits and two time limits. Select between 1 ns and 20 s Trigger on edge rates. Select limits for dV, dt, and slope. Select edge limits between 1 ns and 20 ns Trigger on edge rates. Select limits for dV, dt, and slope. Select edge limits between 1 ns and 20 ns Trigger on edge rates. Select limits for dV, dt, and slope. Select edge limits between 1 ns and 20 ns Trigger on edge rates. Select limits for dV, dt, and slope. Select edge limits between 1 ns and 20 ns Trigger on edge rates. Select limits for dV, dt, and slope	33 1 7									
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	* *	. 101								
HOMOTE SERBITO DEL MECHT THE DITOL STADE AND THE IAST STADE										

LabMaster 10 Zi Series	20 GHz	25 GHz	30 GHz	36 GHz	50 GHz	59 GHz	65 GHz	100 GHz
High-speed Serial Proto								
Data Rates	Option LM10Zi-6GBIT-80B-8B10B-TD: 600 Mb/s to 6.5 Gb/s, Channel 4 input only Option LM10Zi-14GBIT-80B-8B10B-TD: 600 Mb/s to 14.1 Gb/s, Channel 4 input only 600 Mb/s to 14.1 Gb/s, Channel 4 input only (Note: Channel 3 input will capture signal for triggering when oscilloscope is in ≥25 GHz mode)							ut only 3-TD: out only gnal for
Pattern Length					ght 8b/10b symb	ols	•	
Clock and Data Outputs			No Clo	ock and Data Re	covery outputs p	rovided		
Color Waveform Display								
Туре		Or	n LabMaster MC	M-Zi-A Master C	Control Module: C	olor 15.3" flat pa	anel	
			TFT-Active		high resolution t	ouch screen		
Resolution					0 x 768 pixels			
Number of Traces	D				y display channe			es
Grid Styles		Auto, Sin			e + X-Y, Dual + X-		en, I wenty	
Waveform Representation			Sai	mple dots joined	, or sample dots	only		
Integrated Second Displ								
Type	Suppo				econd display wi		ability.	
-		(Note: touch			<u>iy may not be a F</u>	ujitsu driver)		
Resolution			Determine	ed by display cho	sen by user			
High-Speed Digitizer Ou	tput (Option)							
Type					MCM-Zi-A Maste			
					oy a LabMaster 1			
Transfer Rates					nnels (consult Te		or >4 channels)	
Output Protocol Control Protocol		Р	CI Express, Gen	TCP/IP	ed for data transf	er)		
Command Set		Via Window	s Automation, o		eCroy Remote Co	ommand Set		
Draceses (CDL)				,	•			
Processor/CPU Type	In LahMaster	MCM-7i-Δ Mas	eter Control Mod	lule: Intel® Yeon	™ X5660 2.8 GHz	(or hetter) The	are two proc	essors in each
Турс					20 cores and an e			
Processor Memory	0. 0/ 0	<u>a cao p.occ</u>			92 GB optionally		<u> </u>	0 01 121
Operating System					rofessional Edition			
Real Time Clock	Date and	time displayed	with waveform	in hardcopy files	. SNTP support t	o synchronize t	o precision inter	rnal clocks
Setup Storage								
Front Panel and		Store to the	e internal hard d	rive, over a netw	ork, or to a USB-	connected perip	heral device	
Instrument Status								
Interface			,	,	,			
Remote Control		Via			edyne LeCroy Re		d Set	
Network Communication Standard			VXI-1	1 or VICP, LXI CI	ass C (v1.2) Com	npliant		
GPIB Port (optional)					MCM-Zi-A Maste			
LOID Dant (anti	Our market DOI				_abMaster 10-xx			Operatural NA1-1
LSIB Port (optional)	Supports PCI6				ed API. Installs ir d by a LabMaste			
Ethernet Port					Ethernet interfa			
USB Ports					Master Control N			
		minimum :	2 total USB 2.0 ¡	oorts on rear of u	unit to support W	indows compat	tible devices	
					Master Control N			
		minimum 3	3 total USB 2.0 p	orts on front of	unit to support V	<u>/indows compa</u>	tible devices	
External Monitor Port					1-Zi-A Master Coi x 1600 pixel) res			

Warranty and Service

25 GHz LabMaster 10 Zi Series **20 GHz 30 GHz** 36 GHz 50 GHz 59 GHz 65 GHz 100 GHz **Power Requirements** LabMaster 10-xxZi-A Acquisition Module: Voltage 100-240 VAC ±10% at 45-66 Hz; 100-120 VAC ±10% at 380-420 Hz; Automatic AC Voltage Selection, Installation Category II LabMaster MCM-Zi-A Master Control Module: 100-240 VAC ±10% at 45-66 Hz: Automatic AC Voltage Selection, Installation Category II LabMaster 10-xxZi-A Acquisition Module - 1225 W / 1225 VA. LabMaster 10-xxZi-A Acquisition Module -Max. Power Consumption 1275 W / 1275 VA. LabMaster MCM-Zi-A Master Control Module - 450 W / 450 VA. Each Module and the CPU has a separate power cord. LabMaster MCM-Zi-A Master Control Module -450 W / 450 VA. Each Module and the CPU has a separate power cord. **Environmental** +5 °C to +40 ° Temperature (Operating) Temperature -20 °C to +60 °C (Non-Operating) Humidity (Operating) 5% to 80% relative humidity (non-condensing) up to +31 °C Upper limit derates to 50% relative humidity (non-condensing) at +40 °C Humidity (Non-Operating) 5% to 95% relative humidity (non-condensing) as tested per MIL-PRF-28800F Altitude (Operating) Up to 10,000 ft. (3048 m) at or below +25 °C Altitude (Non-Operating) Up to 40,000 ft. (12,192 m) Random Vibration 0.5 g_{rms} 5 Hz to 500 Hz, 15 minutes in each of three orthogonal axes (Operating) Random Vibration 2.4 grms 5 Hz to 500 Hz, 15 minutes in each of three orthogonal axes (Non-Operating) **Functional Shock** 20 gpeak, half sine, 11 ms pulse, 3 shocks (positive and negative) in each of three orthogonal axes, 18 shocks total **Physical Dimensions** Dimensions (HWD) LabMaster MCM-Zi-A Master Control Module - 10.9"H x 18.2"W x 15.6"D (277 x 462 x 396 mm), LabMaster 10-xxZi-A Acquisition Module - 8.0"H x 18.2"W x 26"D (202 x 462 x 660 mm) Weight LabMaster 10-xxZi-A Acquisition Module -LabMaster 10-xxZi-A Acquisition Module -53 lbs. (24 kg) 58 lbs. (24 kg) LabMaster MCM-Zi-A Master Control Module -LabMaster MCM-Zi-A Master Control Module -47 lbs. (21.4 kg) 47 lbs. (21.4 kg) Shipping Weight LabMaster 10-xxZi-A Acquisition Module -LabMaster 10-xxZi-A Acquisition Module -71 lbs. (32.3 kg) 76 lbs. (34.5 kg) LabMaster MCM-Zi-A Master Control Module -LabMaster MCM-Zi-A Master Control Module -56 lbs. (25.5 kg) 56 lbs. (25.5 kg) **Certifications** CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12

3-year warranty; calibration recommended annually.

Optional service programs include extended warranty, upgrades, and calibration services

ORDERING INFORMATION

Product Description

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Product Description

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LabMaster 10 Zi-A Series Master Control Modules

LabMaster Master Control Module with 15.3"	LabMaster MCM-Zi-A
WXGA Color Display.	
SDA Master Control Module with 15.3" WXGA Color	SDA MCM-Zi-A
Display (provides add'l standard software and	
64 Mpt/Ch memory)	

LabMaster 10 Zi-A Series Acquisition Modules

LabMaster 10-207i-A
LUDIVIUSICI TO ZUZI A
LabMaster 10-25Zi-A
LabMaster 10-30Zi-A
LabMaster 10-36Zi-A
LabMaster 10-50Zi-A
LabMaster 10-59Zi-A
Labmaster 10-65Zi-A
Labmaster 10-100Zi-A

Included with LabMaster MCM-Zi-A Standard Configuration

Power Cable for the Destination Country, Optical 3-button Wheel Mouse USB 2.0, Printed Getting Started Manual, Anti-virus Software (Trial Version), Microsoft Windows 7 License, Commercial NIST Traceable Calibration with Certificate, 3-year Warranty

Included with LabMaster 10-xxZi-A Standard Configuration

2.92mm Connector Saver: Qty. 4, 1.85mm Barrel Adapter: Qty. 2 (50-65 GHz units only), PCIe x 8 cable, 2m long, PCIe x 4 cable, 2m long, Power Cable for the Destination Country, ChannelSync 10 GHz clock cable, 2m long, Commercial NIST Traceable Calibration with Certificate, 3-year Warranty

ChannelSync Expansion Products

ChannelSync Mainframe Hub to permit	LabMaster CMH20-Zi
LabMaster expansion to up to	
20 acquisition modules	
Expansion ChannelSync module card for	LabMaster CMH-1ACQMODULE-Zi
ChannelSync Mainframe Hub.	
One required per connected	
acquisition module	

Memory Options

32 Mpts/Ch Standard Memory for LabMaster 10 Zi Acquisition Module	LM10Zi-STD
64 Mpts/Ch Standard Memory for LabMaster 10 Zi	SDA10Zi-STD
Acquisition Module. Used with SDA MCM-Zi	
64 Mpts/Ch Memory Option for LabMaster 10 Zi	LM10Zi-M-64
Acquisition Modules	
128 Mpts/Ch Memory Option for LabMaster 10 Zi	LM10Zi-L-128
Acquisition Modules	
128 Mpts/Ch Memory Option for LabMaster 10 Zi	SDA10Zi-L-128
Acquisition Modules. Used with SDA MCM-Zi-A	
256 Mpts/Ch Memory Option for LabMaster 10 Zi	LM10Zi-L-256
Acquisition Modules	
256 Mpts/Ch Memory Option for LabMaster 10 Zi	SDA10Zi-L-256
Acquisition Modules. Used with SDA MCM-Zi-A	
512 Mpts/Ch Memory Option for LabMaster 10 Zi	LM10Zi-XL-512
Acquisition Modules	
512 Mpts/Ch Memory Option for LabMaster 10 Zi	SDA10Zi-XL-512
Acquisition Modules. Used with SDA MCM-Zi	

Product Description

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CPU, Computer and Other Hardware Options for LabMaster MCM-Zi Master Control Module

Additional 500 GB Hard Drive for MCM-Zi-A	MCM-Zi-500GB-RHD-02
Upgrade to 64 GB RAM for MCM-Zi-A	MCMZI-32-UPG-64GB
Upgrade to 128 GB RAM for MCM-Zi-A	MCMZI-32-UPG-128GB
Upgrade to 192 GB RAM for MCM-Zi-A	MCMZI-32-UPG-192GB
GPIB Option for LabMaster MCM-Zi-A	GPIB-3

Serial Data and Crosstalk Analysis

Bundle - Multi-Lane SDA LinQ	LM10Zi-SDAIII-CompleteLinQ
Framework, including Eye, Jitter, Noise,	SDA10Zi-CompleteLinQ
Crosstalk Measurements, with EyeDrII	DDA10Zi-CompleteLinQ
and VirtualProbe	
Multi-Lane Serial Data Analysis LinQ	LM10Zi-SDAIII-CrossLinQ
Framework, Eye, Jitter, Noise and	SDA10Zi-CrossLinQ
Crosstalk Measurements	DDA10Zi-CrossLinQ
Multi-Lane Serial Data Analysis LinQ	LM10Zi-SDAIII-LinQ
Framework, Eye and Jitter Measurements	SDA10Zi-LinQ
	DDA10Zi-LinQ
Single-Lane Serial Data Analysis	LM10Zi-SDAIII-Crosstalk
Framework, Eye, Jitter, Noise and	SDA10Zi-Crosstalk
Crosstalk Measurements	DDA10Zi-Crosstalk
Single-Lane Serial Data Analysis Framework,	LM10Zi-SDAIII
Eye and Jitter Measurements	
PAM4 Eye, Jitter and Noise Analysis	LM10ZI-PAM4

Signal Integrity Toolkits

Advanced De-embedding, Emulation and	LM10Zi-VIRTUALPROBE
Virtual Probing Toolkit	
Signal Integrity Toolkit - Channel & Fixture	LM10Zi-EYEDRII
De-embedding/Emulation, Tx/Rx Equalization	
Bundle - EyeDrII and VirtualProbe Toolkits	LM10Zi-EYEDRII-VP
Cable De-embed Option	LM10Zi-CBL-DE-EMBED

Serial Data Compliance

Serial Data Compliance	
QualiPHY Enabled 10GBase-KR Software Option	QPHY-10GBase-KR
QualiPHY Enabled 10GBase-T Software Option.	QPHY-10GBase-T
QualiPHY Enabled LPDDR2 Software Option	QPHY-LPDDR2
QualiPHY Enabled DDR3 Software Option	QPHY-DDR3
QualiPHY Enabled DDR4 Software Option	QPHY DDR4
QualiPHY Enabled DisplayPort Software Option	QPHY-DisplayPort
QualiPHY Enabled HDMI Software Option	QPHY-HDMI [†]
QualiPHY Enabled PCIe 3.0 Software Option	QPHY-PCle3
QualiPHY Enabled PCIe Gen1 Software Option	QPHY-PCIe
QualiPHY Enabled SATA Software Option	QPHY-SATA-TSG-RSG
QualiPHY Enabled SAS-2 Software Option	QPHY-SAS2
QualiPHY Enabled SAS3 Software Option	QPHY-SAS3
QualiPHY Enabled SFI Software Option	QPHY-SFI
QualiPHY Enabled SuperSpeed USB Transmitter/	QPHY-USB3-Tx-Rx
Receiver Compliance Software Option	

[†]TF-HDMI-3.3V-QUADPAK required.

PCI Express, SuperSpeed USB (USB 3.0) and SATA Complete Hardware/Software Test Solutions are available. Consult Factory.

Serial Data Test Fixtures

Product Description

HDMI 50 Ω Pull-Up Terminator	TF-HDMI-3.3V
HDMI Pull-Up Terminator Quad Pack	TF-HDMI-3.3V-QUADPAK
SATA 1.5 Gb/s, 3.0 Gb/s and 6.0 Gb/s	TF-SATA-C
Compliance Test Fixture	
SATA 1.5 Gb/s, 3.0 Gb/s and 6.0 Gb/s Compliance Test Fixture Measure Kit	TF-SATA-C-KIT
SuperSpeed USB Compliance Test Fixture	TF-USB3
100 ps Rise Time Filter	RISE-TIME-FILTER-100PS
150 ps Rise Time Filter	RISE-TIME-FILTER-150PS
20 dB SMA Attenuators	20DB-SMA-ATTENUATOR

Product Code

Serial Data Triggers and Decoders	
600 Mb/s to 14.1 Gb/s 80-bit NRZ,	LM10ZI-14GBIT-80B-SYMBOL-TD
8b/10b and 64b/66b Serial Trigger. Also	
includes 8b/10b and 64b/66b Decode.	LAMON CODITION OVALOU TO
600 Mb/s to 6.5 Gb/s 80-bit NRZ, 8b/10b, 64b/66b Serial Trigger. Also	LM10ZI-6GBIT-80B-SYMBOL-TD
includes 8b/10b abd 64b/66b Decode.	
64b/66b Decode Annotation Option	LM10Zi-64b66b D
8b/10b Decode Decode Annotation Option	LM10Zi-8B10B D
ENET Decode Option	LM10Zi-ENETbus D
Ethernet 10G Decode Option	LM10Zi-ENET10Gbus D
PCI Express Decode Annotation Option	LM10Zi-PCIEbus D
USB 3.0 Decode Annotation Option	LM10Zi-USB3bus D
USB 2.0 Decode Annotation Option	LM10Zi-USB2bus D
USB2-HSIC Decode Option	LM10Zi-USB2-HSICbus D
SATA Decode Annotation Option	LM10Zi-SATAbus D
SAS Decode Annotation Option	LM10Zi-SASbus D
Fibre Channel Decode Annotation Option	LM10Zi-FCbus D
D-PHY Decode Option	LM10Zi-DPHYbus D
DigRF 3G Decode Option	LM10Zi-DigRF3Gbus D
DigRF v4 Decode Option	LM10Zi-DIGRFv4bus D
Audiobus and Decode Option for I ² S, LJ, RJ, and TDM	LM10Zi-Audiobus D
Audiobus, Decode, and Graph Option for I ² S, LJ, RJ, and TDM	LM10Zi-Audiobus DG
Manchester Decode Option	LM10Zi-Manchesterbus D
MIPI D-PHY Decode Annotation Option	LM10Zi-DPHYbus D
MIPI D-PHY Decode and Physical Layer Tes	
MIPI M-PHY Decode Annotation Option	LM10Zi-MPHYbus D
MIPI M-PHY Decode Annotation and Physic	al Layer LM10Zi-MPHYbus DP
Test Option	
I ² C Bus and Decode Option	LM10Zi-I2Cbus D
SPI Bus and Decode Option	LM10Zi-SPIbus D
LIN and Decode Option	LM10Zi-LINbus D
UART and RS-232 and Decode Option	LM10Zi-UART-RS232bus D
FlexRay and Decode Option	LM10Zi-FlexRaybus D
FlexRay, Decode, and Physical Layer Test Option	LM10Zi-FlexRaybus DP
CAN and Decode Option	LM10Zi-CANbus D
CAN, Decode and Measure/Graph Option	LM10Zi-CANbus DM
MIL-STD-1553 Decode Option	LM10Zi-1553 D
ARINC 429 Symbolic Decode Option	LM10Zi-ARINC429bus DSymbolic
PROTObus MAG Serial Debug Toolkit	LM10Zi-PROTObus MAG
Decode Annotation and Protocol Analyzer Synchronization Software Option	LM10Zi-ProtoSync
Decode Annotation and Protocol Analyzer	LM10Zi-ProtoSync-BT
Synchronization Software + Bit Tracer Option SENT Decode Option	I M107i-SENTbus D
OLIVI Decode Option	LIVITUZI SLIVIDUS D

ORDERING INFORMATION

Product Description

Product Code

Product Description Product Code

General Purpose and Application Specific Software Options

Spectrum Analysis Option	LM10Zi-SPECTRUM
Digital Filter Software Package	LM10Zi-DFP2
Serial Data Mask Software Package	LM10Zi-SDM
Disk Drive Measurements Software Package	LM10Zi-DDM2
Disk Drive Analyzer Software Package	LM10Zi-DDA
Advanced Optical Recording Measurement Package	LM10Zi-AORM
EMC Pulse Parameter Software Package	LM10Zi-EMC
Clock Jitter Analysis with Four Views Software Package	LM10Zi-JITKIT

High Speed Output Accessories

High-speed PCIe Gen 1 x4 Digitizer Output	LSIB-2
PCI Express x1 Express Card Host Interface for	LSIB-HOSTCARD
Laptop Express Card Slot	
PCI Express x1 Host Interface Board for Desktop PC	LSIB-HOSTBOARD
PCI Express x4 3-meter Cable	LSIB-CABLE-3M
with x4 Cable Connectors Included	
PCI Express x4 7-meter Cable	LSIB-CABLE-7M
with x4 Cable Connectors Included	

Miscellaneous

MCM-Zi-A Rackmount Kit	MCM-Zi-RACKMOUNT
LabMaster 10 Zi-A Acquisition Module	LM10Zi-ACQMOD-RACKMOUNT
Rackmount Kit	
LabMaster MCM-Zi-A Softcase	MCM-Zi-SOFTCASE
LabMaster 10 Zi-A Acquisition Module Soft Carrying Case	LM10Zi-ACQMOD-SOFTCASE

Probes and	Probe A	Accessories
Waval ink 13	GHz 201	/n-n Differential

1 TODES AND TIOSE TIOSESSES	
WaveLink 13 GHz, 2.0 Vp-p Differential Probe System	D1305-A-PS
WaveLink 16 GHz, 2.0 Vp-p Differential Probe System	D1605-A-PS
WaveLink 20 GHz, 2.0Vp-p Differential Probe System	D2005-A-PS
WaveLink 25 GHz, 2.0 Vp-p Differential Probe System	D2505-A-PS
Optical-to-Electrical Converter, DC to 9.5 GHz, 785 to 1550 nm	OE695G
2.92mm to ProLink Adapter with probe power and communications pass through	L2.92A-PLINK
2.92mm to ProBus Adapter with probe power and communications pass through	L2.92A-PBUS
200 MHz, 3.5 pF, 1 MΩ Active Differential Probe	ZD200††
500 MHz, 1.0 pF, Active Differential Probe	ZD500††
1 GHz, 1.0 pF, Active Differential Probe	ZD1000††
1.5 GHz, 1.0 pF, Active Differential Probe	ZD1500††
2.5 GHz, 0.9 pF, 1 MΩ High Impedance Active Probe	ZS2500††
4 GHz, 0.6 pF, 1 MΩ High Impedance Active Probe	ZS4000††
WaveLink 4 GHz, 2.5 Vp-p Differential Probe System	D410-PSTT
WaveLink 4 GHz, 5 Vp-p Differential Probe System	D420-PS††
WaveLink 6 GHz, 2.5 Vp-p Differential Probe System	D610-PS**
WaveLink 6 GHz, 5 Vp-p Differential Probe System	D620-PS**
WaveLink 8 GHz 3.5Vp-p Differential Probe System	D830-PS**
WaveLink 10 GHz 3.5Vp-p Differential Probe System	D1030-PS**
WaveLink 13 GHz 3.5Vp-p Differential Probe System	D1330-PS**
WaveLink 6 GHz Differential Amplifier Module with Adjustable Tip	D600A-AT*
WaveLink 3GHz Differential Amplifier Module with Adjustable Tip	D300A-AT†
WaveLink ProLink Platform/Cable Assembly (4 – 6 GHz)	WL-PLink-CASE**
WaveLink ProBus Platform/Cable Assembly (4 GHz)	WL-PBus-CASETT
SMA/SMP Lead Set for Dxx30 Probes	Dxx30-SMA-SMP Leads

^{*} For a complete probe, order a WL-PLink-CASE Platform/Cable Assembly with the Adjustable Tip Module.

A variety of other active voltage and current probes are also available. Consult Teledyne LeCroy for more information.

Customer Service

Teledyne LeCroy oscilloscopes and probes are designed, built, and tested to ensure high reliability. In the unlikely event you experience difficulties, our digital oscilloscopes are fully warranted for three years and our probes are warranted for one year.

This warranty includes:

- No charge for return shipping
- Long-term 7-year support
- Upgrade to latest software at no charge



1-800-5-LeCroy teledynelecroy.com

Local sales offices are located throughout the world. Visit our website to find the most convenient location.

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 $MATLAB^{\otimes}$ is a registered trademark of The MathWorks, Inc. All other product or brand names are trademarks or requested trademarks of their respective holders.

^{**}Requires purchase and use of L2.92A-PLINK

[†] For a complete probe, order a WL-PBUS-CASE Platform/Cable Assembly with the Adjustable Tip Module

^{††} Requires purchase and use of L2.92A-PBUS